

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
2				*****
3	*			
4	*			Zvector E6 instruction tests for VRR-i encoded:
5	*			
6	*	E650	VCVB	- VECTOR CONVERT TO BINARY (32)
7	*	E652	VCV рG	- VECTOR CONVERT TO BINARY (64)
8	*			
9	*			James Wekel June 2024
10				*****
11				
12				*****
13	*			
14	*			basic instruction tests
15	*			
16				*****
17	*			This program tests proper functioning of the z/arch E6 VRR-i vector
18	*			convert to binary instructions. Exceptions are not tested.
19	*			
20	*			PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
21	*			obvious coding errors. None of the tests are thorough. They are
22	*			NOT designed to test all aspects of any of the instructions.
23	*			
24				*****
25	*			
26	*			*Testcase zvector-e6-11-convertbinary: VECTOR E6 VRR-i instruction
27	*			
28	*			Zvector E6 tests for VRR-i encoded instruction:
29	*			
30	*			E650 VCVB - VECTOR CONVERT TO BINARY (32)
31	*			E652 VCVBG - VECTOR CONVERT TO BINARY (64)
32	*			
33	*			# -----
34	*			# This tests only the basic function of the instruction.
35	*			# Exceptions are NOT tested.
36	*			# -----
37	*			
38	*	mainsize	2	
39	*	numcpu	1	
40	*	sysclear		
41	*	archlvl	z/Arch	
42	*			
43	*	diag8cmd	enable	# (needed for messages to Hercules console)
44	*	loadcore	"\$(testpath)/zvector-e6-11-convertbinary.core"	0x0
45	*	diag8cmd	disable	# (reset back to default)
46	*			
47	*			*Done
48				*****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
50				*****
51	*			FCHECK Macro - Is a Facility Bit set?
52	*			
53	*			If the facility bit is NOT set, an message is issued and
54	*			the test is skipped.
55	*			
56	*			Fcheck uses R0, R1 and R2
57	*			
58	* eg.			FCHECK 134, 'vector-packed-decimal'
59				*****
60				MACRO
61				FCHECK &BITNO, &NOTSETMSG
62	. *			&BITNO : facility bit number to check
63	. *			&NOTSETMSG : 'facility name'
64		LCLA	&FBBYTE	Facility bit in Byte
65		LCLA	&FBBIT	Facility bit within Byte
66				
67		LCLA	&L(8)	
68	&L(1)	SetA	128, 64, 32, 16, 8, 4, 2, 1	bit positions within byte
69				
70	&FBBYTE	SETA	&BITNO/8	
71	&FBBIT	SETA	&L((&BITNO-(&FBBYTE*8))+1)	
72	. *	MNOTE	0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'	
73				
74		B	X&SYSNDX	
75	*			Fcheck data area
76	*			skip messgae
77	SKT&SYSNDX	DC	C'	Skipping tests:
78		DC	C&NOTSETMSG	
79		DC	C'	facility (bit &BITNO) is not installed.'
80	SKL&SYSNDX	EQU	*- SKT&SYSNDX	
81	*			facility bits
82		DS	FD	gap
83	FB&SYSNDX	DS	4FD	
84		DS	FD	gap
85	*			
86	X&SYSNDX	EQU	*	
87		LA	R0, ((X&SYSNDX- FB&SYSNDX)/8)-1	
88		STFLE	FB&SYSNDX	get facility bits
89				
90		XGR	R0, R0	
91		IC	R0, FB&SYSNDX+&FBBYTE	get fbit byte
92		N	R0, =F' &FBBIT'	is bit set?
93		BNZ	XC&SYSNDX	
94	*			
95	*			facility bit not set, issue message and exit
96	*			
97		LA	R0, SKL&SYSNDX	message length
98		LA	R1, SKT&SYSNDX	message address
99		BAL	R2, MSG	
100				
101		B	EOJ	
102	XC&SYSNDX	EQU	*	
103			MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STM		
				105 **** 106 * Low core PSWs 107 ****		
00000000		00000000 00000000	00002227	109 ZVE6TST START 0 110 USING ZVE6TST, R0		Low core addressability
		00000140	00000000	112 SVOLDPSW EQU ZVE6TST+X' 140'		z/Arch Supervisor call old PSW
00000000		00000000 000001A0		114 ORG ZVE6TST+X' 1A0' 115 DC X' 0000000180000000' 116 DC AD(BEGIN)		z/Architecture RESTART PSW
000001B0		000001B0 000001D0		118 ORG ZVE6TST+X' 1D0' 119 DC X' 0002000180000000' 120 DC AD(X' DEAD')		z/Architecture PROGRAM CHECK PSW
000001E0		000001E0 00000200		122 ORG ZVE6TST+X' 200' 123		Start of actual test program ..

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				125 **** 126 * The actual "ZVE6TST" program itself... 127 **** 128 * 129 * Architecture Mode: z/Arch 130 * Register Usage: 131 * 132 * R0 (work) 133 * R1-4 (work) 134 * R5 Testing control table - current test base 135 * R6-R7 (work) 136 * R8 First base register 137 * R9 Second base register 138 * R10 Third base register 139 * R11 E6TEST call return 140 * R12 E6TESTS register 141 * R13 (work) 142 * R14 Subroutine call 143 * R15 Secondary Subroutine call or work 144 * 145 ****
00000200		00000200		147 USING BEGIN, R8 FIRST Base Register
00000200		00001200		148 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		149 USING BEGIN+8192, R10 THIRD Base Register
00000200	0580			150
00000202	0680			151 BEGIN BALR R8, 0 Initialize FIRST base register
00000204	0680			152 BCTR R8, 0 Initialize FIRST base register
				153 BCTR R8, 0 Initialize FIRST base register
00000206	4190 8800		00000800	154 LA R9, 2048(, R8) Initialize SECOND base register
0000020A	4190 9800		00000800	155 LA R9, 2048(, R9) Initialize SECOND base register
0000020E	41A0 9800		00000800	156 LA R10, 2048(, R9) Initialize THIRD base register
00000212	41A0 A800		00000800	157 LA R10, 2048(, R10) Initialize THIRD base register
00000216	B600 8334		00000534	158 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 8335		00000535	159 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 8335		00000535	160 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 8334		00000534	161 LCTL R0, R0, CTLR0 Reload updated CRO
				162
				163
				164
				165
				166 ****
				167 * Is Vector packed-decimal facility installed (bit 134)
				168 ****
				169
00000226	47F0 80B0		000002B0	170 FCHECK 134, 'vector-packed-decimal'
				171+ B X0001
				172+* Fcheck data area
				173+* skip message
0000022A	40404040 40404040		174+SKT0001	C' Skipping tests: '
00000244	A58583A3 96996097		175+	DC C' vector-packed-decimal'
00000259	40868183 899389A3	00000054	176+SKL0001	DC C' facility (bit 134) is not installed.'
		00000001	177+SKL0001	EQU *- SKT0001
			178+*	facility bits
00000280	00000000 00000000		179+ DS FD	gap
00000288	00000000 00000000		180+FB0001 DS 4FD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000002A8	00000000 00000000			181+ 182+*	DS	FD	gap
000002B0	4100 0004	000002B0	00000001	183+X0001	EQU *		
000002B4	B2B0 8088		00000004	184+	LA	R0, ((X0001-FB0001)/8)-1	
000002B8	B982 0000		00000288	185+	STFLE FB0001		get facility bits
000002BC	4300 8098		00000298	186+	XGR	RO, RO	
000002C0	5400 833C		0000053C	187+	IC	RO, FB0001+16	get fbit byte
000002C4	4770 80D8		000002D8	188+	N	RO, =F' 2'	is bit set?
				189+	BNZ XC0001		
				190+*			
				191+* facility bit not set, issue message and exit			
				192+*			
000002C8	4100 0054		00000054	193+	LA	R0, SKL0001	message length
000002CC	4110 802A		0000022A	194+	LA	R1, SKT0001	message address
000002D0	4520 8250		00000450	195+	BAL	R2, MSG	
000002D4	47F0 8318		00000518	196+	B	EOJ	
		000002D8	00000001	197+XC0001	EQU *		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				199 ****	*****	*****	*****
				200 *	Do tests in the E6TESTS table		
				201 ****	*****	*****	*****
000002D8	58C0 8340		00000540	203 L R12, =A(E6TESTS)		get table of test addresses	
				204			
000002DC	5850 C000	000002DC	00000001	205 NEXTE6 EQU *		get test address	
000002E0	1255		00000000	206 L R5, 0(0, R12)		have a test?	
000002E2	4780 820C		0000040C	207 LTR R5, R5			
				208 BZ ENDTEST		done?	
000002E6	B982 0000			210 XGR R0, R0		no cc error	
000002EA		00000000		211 USING E6TEST, R5			
000002EA	4800 5004		00000004	213			
000002EE	5000 8E04		00001004	214 LH R0, TNUM		save current test number	
				215 ST R0, TESTING		for easy reference	
000002F2	58B0 5000		00000000	216 L R11, TSUB		get address of test routine	
000002F6	05BB			217 BALR R11, R11		do test	
000002F8	E310 5009 0076		00000009	219 LB R1, CCMASK		(failure CC mask)	
000002FE	8910 0004		00000004	220 SLL R1, 4		(shift to BC instr CC position)	
00000302	4410 811E		0000031E	221 EX R1, TESTCC		fail if...	
		00000306	00000001	222			
00000306	E310 5018 0014	00000306	00000001	223 TESTREST EQU *			
0000030C	D507 8F20 1000	00001120	00000000	224 LGF R1, READDR		get address of expected result	
00000312	4770 81B2		000003B2	225 CLC R10OUTPUT, 0(R1)		valid?	
				226 BNE FAILMSG		no, issue failed message	
00000316	41C0 C004		00000004	227			
0000031A	47F0 80DC		000002DC	228 LA R12, 4(0, R12)		next test address	
				229 B NEXTE6			
0000031E	4700 8122		00000322	230 231 TESTCC BC 0, CCMSG		(fail if unexpected condition code)	
				232			
				233			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				235 ****		
				236 * cc was not as expected		
				237 ****		
00000322	E310 0001 0082	00000322	00000001	238 CCMSG EQU *		
00000328	E310 5007 0076		00000001	239 XG R1, R1		
0000032E	5410 8344		00000007	240 LB R1, MB	m3 has CS bit	
00000332	4780 8106		00000544	241 N R1, =F' 1'	get CS (CC set) bit	
			00000306	242 BZ TESTREST	ignore if not set	
				243 *		
				244 * extract CC extracted PSW		
				245 *		
00000336	5810 8ED8		000010D8	246 L R1, CCPSW		
0000033A	8810 000C		0000000C	247 SRL R1, 12		
0000033E	5410 8348		00000548	248 N R1, =XL4' 3'		
00000342	4210 8EE0		000010E0	249 STC R1, CCFOUND	save cc	
				250 *		
				251 * FILL IN MESSAGE		
				252 *		
00000346	4820 5004		00000004	253 LH R2, TNUM	get test number and convert	
0000034A	4E20 8EC8		000010C8	254 CVD R2, DECNUM		
0000034E	D211 8EB2 8E9C	000010B2	0000109C	255 MVC PRT3, EDIT		
00000354	DE11 8EB2 8EC8	000010B2	000010C8	256 ED PRT3, DECNUM		
0000035A	D202 8E57 8EBF	00001057	000010BF	257 MVC CCPRTNUM(3), PRT3+13	fill in message with test #	
00000360	D207 8E74 500A	00001074	0000000A	258		
				259 MVC CCPRTNAME, OPNAME	fill in message with instruction	
				260		
00000366	B982 0022			261 XGR R2, R2	get CC as U8	
0000036A	4320 5008		00000008	262 IC R2, CC		
0000036E	4E20 8EC8		000010C8	263 CVD R2, DECNUM	and convert	
00000372	D211 8EB2 8E9C	000010B2	0000109C	264 MVC PRT3, EDIT		
00000378	DE11 8EB2 8EC8	000010B2	000010C8	265 ED PRT3, DECNUM		
0000037E	D200 8E8A 8EC1	0000108A	000010C1	266 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field	
				267		
00000384	B982 0022			268 XGR R2, R2	get CCFOUND as U8	
00000388	4320 8EE0		000010EO	269 IC R2, CCFOUND		
0000038C	4E20 8EC8		000010C8	270 CVD R2, DECNUM	and convert	
00000390	D211 8EB2 8E9C	000010B2	0000109C	271 MVC PRT3, EDIT		
00000396	DE11 8EB2 8EC8	000010B2	000010C8	272 ED PRT3, DECNUM		
0000039C	D200 8E9A 8EC1	0000109A	000010C1	273 MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound	
				274		
000003A2	4100 0055		00000055	275 LA R0, CCPRTLNG	message length	
000003A6	4110 8E47		00001047	276 LA R1, CCPRTLINE	messagfe address	
000003AA	45F0 821A		0000041A	277 BAL R15, RPERROR		
000003AE	47F0 81FC		000003FC	278 B FAILCONT		
				279		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				281 ****			
				282 * result not as expected:			
				283 * issue message with test number, instruction under test			
				284 * and instruction 12			
				285 ****			
000003B2	4820 5004	000003B2	00000001	286 FAILMSG EQU *			get test number and convert
000003B6	4E20 8EC8		00000004	287 LH R2, TNUM			
			000010C8	288 CVD R2, DECNUM			
000003BA	D211 8EB2 8E9C	000010B2	0000109C	289 MVC PRT3, EDIT			
000003C0	DE11 8EB2 8EC8	000010B2	000010C8	290 ED PRT3, DECNUM			
000003C6	D202 8E18 8EBF	00001018	000010BF	291 MVC PRTNUM(3), PRT3+13			fill in message with test #
000003CC	D207 8E33 500A	00001033	0000000A	292			
				293 MVC PRTNAME, OPNAME			fill in message with instruction
000003D2	B982 0022			294			
000003D6	4320 5007		00000007	295 XGR R2, R2			get M8 as U8
000003DA	4E20 8EC8		000010C8	296 IC R2, M8			and convert
000003DE	D211 8EB2 8E9C	000010B2	0000109C	297 CVD R2, DECNUM			
000003E4	DE11 8EB2 8EC8	000010B2	000010C8	298 MVC PRT3, EDIT			
000003EA	D201 8E44 8EC0	00001044	000010C0	299 ED PRT3, DECNUM			
				300 MVC PRTMB(2), PRT3+14			fill in message with m8 field
000003F0	4100 003F		0000003F	301			
000003F4	4110 8E08		00001008	302 LA R0, PRTLNG			message length
000003F8	45F0 821A		0000041A	303 LA R1, PRTLINE			messagfe address
				304 BAL R15, RPERROR			
				306 ****			
				307 * continue after a failed test			
				308 ****			
000003FC	5800 8344	000003FC	00000001	309 FAILCONT EQU *			
00000400	5000 8E00		00000544	310 L R0, =F' 1'			set GLOBAL failed test indicator
			00001000	311 ST R0, FAILED			
00000404	41C0 C004		00000004	312			
00000408	47F0 80DC		000002DC	313 LA R12, 4(0, R12)			next test address
				314 B NEXTE6			
				316 ****			
				317 * end of testing; set ending psw			
				318 ****			
0000040C	5810 8E00	0000040C	00000001	319 ENDTEST EQU *			
00000410	1211		00001000	320 L R1, FAILED			did a test fail?
00000412	4780 8318		00000518	321 LTR R1, R1			
00000416	47F0 8330		00000530	322 BZ EOJ			No, exit
				323 B FAILTEST			Yes, exit with BAD PSW
				324			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				326 ****	*****	*****
				327 * RPTERROR	Report instruction test in error	
				328 *	R0 = MESSGAE LENGTH	
				329 *	R1 = ADDRESS OF MESSAGE	
				330 ****	*****	*****
0000041A	50F0 8238	00000438	332	RPTERROR ST	R15, RPTSAVE	Save return address
0000041E	5050 823C	0000043C	333	ST	R5, RPTSVR5	Save R5
			334 *			
			335 *	Use Hercules Diagnose for Message to console		
			336 *			
00000422	9002 8240	00000440	337	STM	R0, R2, RPTDWSAV	save regs used by MSG
00000426	4520 8250	00000450	338	BAL	R2, MSG	call Hercules console MSG display
0000042A	9802 8240	00000440	339	LM	R0, R2, RPTDWSAV	restore regs
0000042E	5850 823C	0000043C	341	L	R5, RPTSVR5	Restore R5
00000432	58F0 8238	00000438	342	L	R15, RPTSAVE	Restore return address
00000436	07FF		343	BR	R15	Return to caller
00000438	00000000		345	RPTSAVE DC	F' 0'	R15 save area
0000043C	00000000		346	RPTSVR5 DC	F' 0'	R5 save area
00000440	00000000 00000000		348	RPTDWSAV DC	2D' 0'	R0-R2 save area for MSG call

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				350 **** 351 * Issue HERCULES MESSAGE pointed to by R1, length in R0 352 * R2 = return address 353 **** 354			
00000450	4900 834C		0000054C	355 MSG CH R0, =H' 0' 356 BNHR R2		Do we even HAVE a message? No, ignore	
00000454	07D2			357			
00000456	9002 828C		0000048C	358 STM R0, R2, MSGSAVE 359		Save registers	
0000045A	4900 834E			360 CH R0, =AL2(L' MSGMSG)		Message length within limits?	
0000045E	47D0 8266		00000466	361 BNH MSGOK 00000462 4100 005F 0000005F 362 LA R0, L' MSGMSG 363		Yes, continue No, set to maximum	
00000466	1820			364 MSGOK LR R2, R0 365 BCTR R2, 0 00000468 0620 0000046A 4420 8298 366 EX R2, MSGMVC 367		Copy length to work register Minus-1 for execute Copy message to O/P buffer	
0000046E	4120 200A		0000000A	368 LA R2, 1+L' MSGCMD(, R2) 00000472 4110 829E 0000049E 369 LA R1, MSGCMD 370		Calculate true command length Point to true command	
00000476	83120008			371 DC X' 83' , X' 12' , X' 0008' 0000047A 4780 8286 00000486 372 BZ MSGRET 373		Issue Hercules Diagnose X' 008' Return if successful	
0000047E	1222			374 LTR R2, R2 00000480 4780 8286 00000486 375 BZ MSGRET 376		Is Diag8 Ry (R2) 0? an error occurred but continue	
00000484	0000			377 DC H' 0' 378		CRASH for debugging purposes	
00000486	9802 828C		0000048C	379 MSGRET LM R0, R2, MSGSAVE 0000048A 07F2 380 BR R2		Restore registers Return to caller	
0000048C	00000000 00000000			382 MSGSAVE DC 3F' 0' 00000498 D200 82A7 1000 000004A7 00000000 383 MSGMVC MVC MSGMSG(0), 0(R1)		Registers save area Executed instruction	
0000049E	D4E2C7D5 D6C8405C			385 MSGCMD DC C' MSGNOH * ' 000004A7 40404040 40404040 386 MSGMSG DC CL95' ' 387		*** HERCULES MESSAGE COMMAND *** The message text to be displayed	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				389 **** 390 * Normal completion or Abnormal termination PSWs 391 ****	*****
00000508	00020001 80000000			393 EOJPSW DC OD' 0' , X' 0002000180000000' , AD(0)	
00000518	B2B2 8308	00000508	395 EOJ LPSWE EOJPSW		Normal completion
00000520	00020001 80000000			397 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')	
00000530	B2B2 8320	00000520	399 FAILTEST LPSWE FAILPSW		Abnormal termination
				401 **** 402 * Working Storage 403 ****	*****
00000534	00000000		405 CTLR0 DS F		CR0
00000538	00000000		406 DS F		
0000053C			408 LTORG ,		Literals pool
0000053C	00000002		409 =F' 2'		
00000540	00002160		410 =A(E6TESTS)		
00000544	00000001		411 =F' 1'		
00000548	00000003		412 =XL4' 3'		
0000054C	0000		413 =H' 0'		
0000054E	005F		414 =AL2(L' MSGMSG)		
			415		
			416 * some constants		
			417		
	00000400	00000001	418 K EQU 1024		One KB
	00001000	00000001	419 PAGE EQU (4*K)		Size of one page
	00010000	00000001	420 K64 EQU (64*K)		64 KB
	00100000	00000001	421 MB EQU (K*K)		1 MB
			422		
			423		
	AABBCCDD	00000001	424 REG2PATT EQU X' AABBCCDD'		Polluted Register pattern
	000000DD	00000001	425 REG2LOW EQU X' DD'		(last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				427 *=====
				428 *
				429 * NOTE: start data on an address that is easy to display
				430 * within Hercules
				431 *
				432 *=====
				433
00000550		00000550	00001000	434 ORG ZVE6TST+X'1000'
00001000	00000000			435 FAILED DC F'0'
00001004	00000000			436 TESTING DC F'0'
				some test failed? current test number
				438 *****
				439 * TEST failed : result messgae
				440 *****
				441 *
				442 * failed message and associated editting
				443 *
00001008	40404040 40404040			444 PRTLINE DC C' Test # '
00001018	A7A7A7			445 PRTNUM DC C' xxx'
0000101B	40868189 93858440			446 DC C' failed for instruction '
00001033	A7A7A7A7 A7A7A7A7			447 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3 884094F3			448 DC C' with m3='
00001044	A7A7			449 PRTMB DC C' xx'
00001046	4B	0000003F	00000001	450 DC C' . '
				451 PRTLNG EQU *-PRTLINE
				453 *****
				454 * TEST failed : CC message
				455 *****
				456 *
				457 * failed message and associated editting
				458 *
00001047	40404040 40404040			459 CCPRTLINE DC C' Test # '
00001057	A7A7A7			460 CCPRTNUM DC C' xxx'
0000105A	40A69996 95874083			461 DC C' wrong cc for instruction '
00001074	A7A7A7A7 A7A7A7A7			462 CCPRTNAME DC CL8' xxxxxxxx'
0000107C	4085A797 8583A385			463 DC C' expected: cc='
0000108A	A7			464 CCPRTEXP DC C' x'
0000108B	6B			465 DC C' , '
0000108C	40998583 8589A585			466 DC C' received: cc='
0000109A	A7			467 CCPRTGOT DC C' x'
0000109B	4B	00000055	00000001	468 DC C' . '
				469 CCPRTLNG EQU *-CCPRTLINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				503 **** 504 * E6TEST DSECT 505 ****
00000000	00000000			507 E6TEST DSECT ,
00000004	0000			508 TSUB DC A(0) pointer to test 509 TNUM DC H'00' Test Number
00000006	00			510 DC XL1'00'
00000007	00			511 MB DC HL1'00' MB
00000008	00			512 CC DC HL1'00' cc
00000009	00			513 CCMASK DC HL1'00' not expected CC mask
0000000A	40404040 40404040			514 515 OPNAME DC CL8' ' E6 name
00000014	00000000			516 517 RELEN DC A(0) RESULT LENGTH 00000018 00000000 DC A(0) expected result address
				519 520 ** 521 * test routine will be here (from VRR_I macro) 522 * followed by 523 * r1 - expected result (64 bits) (even for VCVB) 524 * v1 - 16 byte packed decimal source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
526				*****
527	*			Macros to help build test tables
528	*			-
529	*			VRR_I Macro to help build test tables
530				*****
531				MACRO
532				VRR_I &INST, &MB, &CC
533	.	*		
534	.	*		&INST - VRS-d instruction under test
535	.	*		&MB - P2 (bit 0), P1 (bit 2) and
536	.	*		CS (bit 3)
537	.	*		&CC - expected CC
538	.	*		note: M4 - bit 0 IOM (always 0)
539	.	*		
540	.	*		
541		LCLA	&XCC(4)	&CC has mask values for FAILED condition codes
542	&XCC(1)	SETA	7	CC != 0
543	&XCC(2)	SETA	11	CC != 1
544	&XCC(3)	SETA	13	CC != 2
545	&XCC(4)	SETA	14	CC != 3
546				
547		GBLA	&TNUM	
548	&TNUM	SETA	&TNUM+1	
549				
550		DS	OFD	
551		USING	*, R5	base for test data and test routine
552				
553	T&TNUM	DC	A(X&TNUM)	address of test routine
554		DC	H' &TNUM	test number
555		DC	XL1' 00'	
556		DC	HL1' &MB'	&MB
557		DC	HL1' &CC'	cc
558		DC	HL1' &XCC(&CC+1)'	cc failed mask
559				
560		DC	CL8' &INST'	instruction name
561		DC	A(16)	result length
562	REA&TNUM	DC	A(RE&TNUM)	result address
563	.	*		
564	X&TNUM	DS	OF	INSTRUCTION UNDER TEST ROUTINE
565		LG	R1, R1FUDGE	pollute R1
566		VL	V1, RE&TNUM+8	get V1 source
567				
568				
569				
570				
571		STG	R1, R1OUTPUT	save
572		EPSW	R2, R0	extract psw
573		ST	R2, CCPSW	to save CC
574				
575		BR	R11	return
576				
577	RE&TNUM	DC	OF	
578		DROP	R5	
579				
580				MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
582				*****
583	*			PTTABLE Macro to generate table of pointers to individual tests
584				*****
585				
586				MACRO
587				PTTABLE
588				GBLA &TNUM
589				LCLA &CUR
590	&CUR			SETA 1
591	. *			
592	TTABLE	DS	OF	
593	. LOOP	ANOP		
594	. *			
595		DC	A(T&CUR)	address of test
596	. *			
597	&CUR	SETA	&CUR+1	
598		AIF	(&CUR LE &TNUM).LOOP	
599	* .			
600		DC	A(0)	END OF TABLE
601		DC	A(0)	
602	. *			
603				MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				605 **** 606 * E6 VRR_I tests 607 ****	***** *****
00001188		00000000	00002227	608 ZVE6TST CSECT, 609 DS OF	
				611 PRINT DATA 612 * 613 * E650 VCVB - VECTOR CONVERT TO BINARY (32) 614 * E652 VCVBG - VECTOR CONVERT TO BINARY (64) 615 * 616 * VRR_I instr, m3, m4 617 * followed by 618 * r1 - expected result (64 bits) (even for VCVB) 619 * v1 - 16 byte packed decimal source 620	
00001188				621 *-- 622 * VCVB - VECTOR CONVERT TO BINARY (32) 623 *--	--
00001188	000011A4	00001188		624 * VCVB simple 625 VRR_I VCVB, 1, 0 626+ DS OFD	
00001188				627+ USING *, R5 628+T1 DC A(X1)	base for test data and test routine address of test routine
0000118C	0001			629+ DC H' 1'	test number
0000118E	00			630+ DC XL1' 00'	&M3
0000118F	01			631+ DC HL1' 1'	cc
00001190	00			632+ DC HL1' 0'	cc failed mask
00001191	07			633+ DC HL1' 7'	instruction name
00001192	E5C3E5C2 40404040			634+ DC CL8' VCVB'	result length
0000119C	00000010			635+ DC A(16)	result address
000011A0	000011C8			636+REA1 DC A(RE1)	INSTRUCTION UNDER TEST ROUTINE
000011A4				637+* 638+X1 DS OF	
000011A4	E310 8EE8 0004		000010E8	639+ LG R1, R1FUDGE	pollute R1
000011AA	E710 5048 0006		000011D0	640+ VL V1, RE1+8	get V1 source
000011B0	E611 0010 0050			641+ VCVB R1, V1, 1	test instruction
000011B6	E310 8F20 0024		00001120	642+ STG R1, R1OUTPUT	save
000011BC	B98D 0020			643+ EPSW R2, R0	extract psw
000011C0	5020 8ED8		000010D8	644+ ST R2, CCPSW	to save CC
000011C4	07FB			645+ BR R11	return
000011C8				646+RE1 DC OF	
000011C8				647+ DROP R5	
000011C8	AABBCCDD 0000000A			648 DC XL08' AABBCCDD0000000A'	R1 result
000011D0	00000000 00000000			649 DC XL16' 000000000000000000000000000010C'	V1 source
000011D8	00000000 0000010C			650	
000011E0				651 VRR_I VCVB, 1, 0 652+ DS OFD	
000011E0	000011FC	000011E0		653+ USING *, R5 654+T2 DC A(X2)	base for test data and test routine address of test routine
000011E4	0002			655+ DC H' 2'	test number
000011E6	00			656+ DC XL1' 00'	&M3
000011E7	01			657+ DC HL1' 1'	cc
000011E8	00			658+ DC HL1' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000011E9	07			659+ DC HL1' 7'	cc failed mask	
000011EA	E5C3E5C2 40404040			660+ DC CL8' VCVB'	instruction name	
000011F4	00000010			661+ DC A(16)	result length	
000011F8	00001220			662+REA2 DC A(RE2)	result address	
				663+*	INSTRUCTION UNDER TEST ROUTINE	
000011FC				664+X2 DS OF		
000011FC	E310 8EE8 0004	000010E8	665+ LG R1, R1FUDGE	pollute R1		
00001202	E710 9028 0006	00001228	666+ VL V1, RE2+8	get V1 source		
00001208	E611 0010 0050		667+ VCVB R1, V1, 1	test instruction		
0000120E	E310 8F20 0024	00001120	668+ STG R1, R1OUTPUT	save		
00001214	B98D 0020		669+ EPSW R2, R0	extract psw		
00001218	5020 8ED8	000010D8	670+ ST R2, CCPSW	to save CC		
0000121C	07FB		671+ BR R11	return		
00001220			672+REA2 DC OF			
00001220			673+ DROP R5			
00001220	AABBCCDD FFFFFFF6		674 DC XL08' AABBCCDDFFFFFF6'	R1 result		
00001228	00000000 00000000		675 DC XL16' 0000000000000000000000000000000010D'	V1 source		
00001230	00000000 0000010D			676		
				677 VRR_I VCVB, 1, 0		
00001238		00001238	678+ DS OFD			
00001238			679+ USING *, R5	base for test data and test routine		
00001238	00001254		680+T3 DC A(X3)	address of test routine		
0000123C	0003		681+ DC H' 3'	test number		
0000123E	00		682+ DC XL1' 00'			
0000123F	01		683+ DC HL1' 1'	&MB		
00001240	00		684+ DC HL1' 0'	cc		
00001241	07		685+ DC HL1' 7'	cc failed mask		
00001242	E5C3E5C2 40404040		686+ DC CL8' VCVB'	instruction name		
0000124C	00000010		687+ DC A(16)	result length		
00001250	00001278		688+REA3 DC A(RE3)	result address		
			689+*	INSTRUCTION UNDER TEST ROUTINE		
00001254			690+X3 DS OF			
00001254	E310 8EE8 0004	000010E8	691+ LG R1, R1FUDGE	pollute R1		
0000125A	E710 5048 0006	00001280	692+ VL V1, RE3+8	get V1 source		
00001260	E611 0010 0050		693+ VCVB R1, V1, 1	test instruction		
00001266	E310 8F20 0024	00001120	694+ STG R1, R1OUTPUT	save		
0000126C	B98D 0020		695+ EPSW R2, R0	extract psw		
00001270	5020 8ED8	000010D8	696+ ST R2, CCPSW	to save CC		
00001274	07FB		697+ BR R11	return		
00001278			698+REA3 DC OF			
00001278			699+ DROP R5			
00001278	AABBCCDD 0008A160		700 DC XL08' AABBCCDD0008A160'	R1 result		
00001280	00000000 00000000		701 DC XL16' 00000000000000000000000000000000565600C'	V1 source		
00001288	00000000 0565600C			702		
				703 VRR_I VCVB, 1, 0		
00001290		00001290	704+ DS OFD			
00001290			705+ USING *, R5	base for test data and test routine		
00001290	000012AC		706+T4 DC A(X4)	address of test routine		
00001294	0004		707+ DC H' 4'	test number		
00001296	00		708+ DC XL1' 00'			
00001297	01		709+ DC HL1' 1'	&MB		
00001298	00		710+ DC HL1' 0'	cc		
00001299	07		711+ DC HL1' 7'	cc failed mask		
0000129A	E5C3E5C2 40404040		712+ DC CL8' VCVB'	instruction name		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000012A4	00000010			713+ DC A(16)	result length	
000012A8	000012D0			714+REA4 DC A(REA4)	result address	
				715+*	INSTRUCTION UNDER TEST ROUTINE	
000012AC				716+X4 DS OF		
000012AC	E310 8EE8 0004	000010E8	717+ LG R1, R1FUDGE	pollute R1		
000012B2	E710 5048 0006	000012D8	718+ VL V1, RE4+8	get V1 source		
000012B8	E611 0010 0050		719+ VCVB R1, V1, 1	test instruction		
000012BE	E310 8F20 0024	00001120	720+ STG R1, R1OUTPUT	save		
000012C4	B98D 0020		721+ EPSW R2, R0	extract psw		
000012C8	5020 8ED8	000010D8	722+ ST R2, CCPSW	to save CC		
000012CC	07FB		723+ BR R11	return		
000012D0			724+REA4 DC OF			
000012D0			725+ DROP R5			
000012D0	AABBCCDD FFF75EA0		726 DC XL08' AABBCCDDFFF75EA0'	R1 result		
000012D8	00000000 00000000		727 DC XL16' 00000000000000000000000000000000565600D'	V1 source		
000012E0	00000000 0565600D		728			
000012E8			729 VRR_I VCVB, 1, 0	INT_MAX		
000012E8		000012E8	730+ DS OFD			
000012E8	00001304		731+ USING *, R5	base for test data and test routine		
000012EC	0005		732+T5 DC A(X5)	address of test routine		
000012EE	00		733+ DC H' 5'	test number		
000012EF	01		734+ DC XL1' 00'			
000012F0	00		735+ DC HL1' 1'	&MB		
000012F1	07		736+ DC HL1' 0'	cc		
000012F2	E5C3E5C2 40404040		737+ DC HL1' 7'	cc failed mask		
000012FC	00000010		738+ DC CL8' VCVB'	instruction name		
00001300	00001328		739+ DC A(16)	result length		
			740+REA5 DC A(REA5)	result address		
00001304			741+*	INSTRUCTION UNDER TEST ROUTINE		
00001304	E310 8EE8 0004	000010E8	742+X5 DS OF			
0000130A	E710 5048 0006	00001330	743+ LG R1, R1FUDGE	pollute R1		
00001310	E611 0010 0050		744+ VL V1, RE5+8	get V1 source		
00001316	E310 8F20 0024	00001120	745+ VCVB R1, V1, 1	test instruction		
0000131C	B98D 0020		746+ STG R1, R1OUTPUT	save		
00001320	5020 8ED8	000010D8	747+ EPSW R2, R0	extract psw		
00001324	07FB		748+ ST R2, CCPSW	to save CC		
00001328			749+ BR R11	return		
00001328			750+REA5 DC OF			
00001328	AABBCCDD 7FFFFFFF		751+ DROP R5			
00001330	00000000 00000000		752 DC XL08' AABBCCDD7FFFFFFF'	R1 result		
00001338	00000214 7483647C		753 DC XL16' 0000000000000000000000002147483647C'	V1 source		
00001340			754			
00001340		00001340	755 VRR_I VCVB, 1, 0	INT_MIN		
00001340	0000135C		756+ DS OFD			
00001344	0006		757+ USING *, R5	base for test data and test routine		
00001346	00		758+T6 DC A(X6)	address of test routine		
00001347	01		759+ DC H' 6'	test number		
00001348	00		760+ DC XL1' 00'			
00001349	07		761+ DC HL1' 1'	&MB		
0000134A	E5C3E5C2 40404040		762+ DC HL1' 0'	cc		
00001354	00000010		763+ DC HL1' 7'	cc failed mask		
00001358	00001380		764+ DC CL8' VCVB'	instruction name		
			765+ DC A(16)	result length		
			766+REA6 DC A(REA6)	result address		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			INSTRUCTION UNDER TEST ROUTINE
0000135C				767+*			
0000135C	E310 8EE8 0004	000010E8	769+	LG	R1, R1FUDGE	pollute R1	
00001362	E710 5048 0006	00001388	770+	VL	V1, RE6+8	get V1 source	
00001368	E611 0010 0050		771+	VCVB	R1, V1, 1	test instruction	
0000136E	E310 8F20 0024	00001120	772+	STG	R1, R1OUTPUT	save	
00001374	B98D 0020		773+	EPSW	R2, R0	extract psw	
00001378	5020 8ED8	000010D8	774+	ST	R2, CCPSW	to save CC	
0000137C	07FB		775+	BR	R11	return	
00001380			776+RE6	DC	OF		
00001380			777+	DROP	R5		
00001380	AABBCCDD 80000000		778	DC	XL08' AABBCCDD80000000'	R1 result	
00001388	00000000 00000000		779	DC	XL16' 000000000000000000002147483648D'	V1 source	
00001390	00000214 7483648D		780				
00001398			781	VRR_I	VCVB, 3, 0	UINT_MAX	
00001398		00001398	782+	DS	OFD		
00001398	000013B4		783+	USING	* , R5	base for test data and test routine	
0000139C	0007		784+T7	DC	A(X7)	address of test routine	
0000139E	00		785+	DC	H' 7'	test number	
0000139F	03		786+	DC	XL1' 00'		
000013A0	00		787+	DC	HL1' 3'	&MB	
000013A1	00		788+	DC	HL1' 0'	cc	
000013A1	07		789+	DC	HL1' 7'	cc failed mask	
000013A2	E5C3E5C2 40404040		790+	DC	CL8' VCVB'	instruction name	
000013AC	00000010		791+	DC	A(16)	result length	
000013B0	000013D8		792+REA7	DC	A(RE7)	result address	
000013B0			793+*			INSTRUCTION UNDER TEST ROUTINE	
000013B4			794+X7	DS	OF		
000013B4	E310 8EE8 0004	000010E8	795+	LG	R1, R1FUDGE	pollute R1	
000013BA	E710 5048 0006	000013E0	796+	VL	V1, RE7+8	get V1 source	
000013C0	E611 0030 0050		797+	VCVB	R1, V1, 3	test instruction	
000013C6	E310 8F20 0024	00001120	798+	STG	R1, R1OUTPUT	save	
000013CC	B98D 0020		799+	EPSW	R2, R0	extract psw	
000013D0	5020 8ED8	000010D8	800+	ST	R2, CCPSW	to save CC	
000013D4	07FB		801+	BR	R11	return	
000013D8			802+RE7	DC	OF		
000013D8			803+	DROP	R5		
000013D8	AABBCCDD FFFFFFFF		804	DC	XL08' AABBCCDDFFFFFF'	R1 result	
000013E0	00000000 00000000		805	DC	XL16' 00000000000000004294967295C'	V1 source	
000013E8	00000429 4967295C		806				
000013F0			807	VRR_I	VCVB, 3, 3	UINT_MAX +1	
000013F0			808+	DS	OFD		
000013F0	0000140C	000013F0	809+	USING	* , R5	base for test data and test routine	
000013F0	0008		810+T8	DC	A(X8)	address of test routine	
000013F4	0008		811+	DC	H' 8'	test number	
000013F6	00		812+	DC	XL1' 00'		
000013F7	03		813+	DC	HL1' 3'	&MB	
000013F8	03		814+	DC	HL1' 3'	cc	
000013F9	0E		815+	DC	HL1' 14'	cc failed mask	
000013FA	E5C3E5C2 40404040		816+	DC	CL8' VCVB'	instruction name	
00001404	00000010		817+	DC	A(16)	result length	
00001408	00001430		818+REA8	DC	A(RE8)	result address	
0000140C			819+*			INSTRUCTION UNDER TEST ROUTINE	
0000140C			820+X8	DS	OF		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000140C	E310 8EE8 0004		000010E8	821+	LG	R1, R1FUDGE	
00001412	E710 5048 0006		00001438	822+	VL	V1, RE8+8	pollute R1 get V1 source
00001418	E611 0030 0050			823+	VCVB	R1, V1, 3	test instruction
0000141E	E310 8F20 0024		00001120	824+	STG	R1, R1OUTPUT	save
00001424	B98D 0020			825+	EPSW	R2, R0	extract psw
00001428	5020 8ED8		000010D8	826+	ST	CCPSW	to save CC
0000142C	07FB			827+	BR	R11	return
00001430				828+RE8	DC	OF	
00001430				829+	DROP	R5	
00001430	AABBCCDD 00000000			830	DC	XL08' AABBCCDD00000000'	R1 result
00001438	00000000 00000000			831	DC	XL16' 00000000000000004294967296C'	V1 source
00001440	00000429 4967296C			832			
				833	VRR_I	VCVB, 1, 3	
00001448		00001448		834+	DS	OFD	
00001448				835+	USING	*, R5	base for test data and test routine
00001448	00001464			836+T9	DC	A(X9)	address of test routine
0000144C	0009			837+	DC	H' 9'	test number
0000144E	00			838+	DC	XL1' 00'	
0000144F	01			839+	DC	HL1' 1'	&MB
00001450	03			840+	DC	HL1' 3'	cc
00001451	0E			841+	DC	HL1' 14'	cc failed mask
00001452	E5C3E5C2 40404040			842+	DC	CL8' VCVB'	instruction name
0000145C	00000010			843+	DC	A(16)	result length
00001460	00001488			844+REA9	DC	A(REA9)	result address
				845+*			INSTRUCTION UNDER TEST ROUTINE
00001464				846+X9	DS	OF	
00001464	E310 8EE8 0004		000010E8	847+	LG	R1, R1FUDGE	pollute R1
0000146A	E710 5048 0006		00001490	848+	VL	V1, RE9+8	get V1 source
00001470	E611 0010 0050			849+	VCVB	R1, V1, 1	test instruction
00001476	E310 8F20 0024		00001120	850+	STG	R1, R1OUTPUT	save
0000147C	B98D 0020			851+	EPSW	R2, R0	extract psw
00001480	5020 8ED8		000010D8	852+	ST	CCPSW	to save CC
00001484	07FB			853+	BR	R11	return
00001488				854+RE9	DC	OF	
00001488				855+	DROP	R5	
00001488	AABBCCDD DF8E1660			856	DC	XL08' AABBCCDDF8E1660'	R1 result
00001490	00000000 00000000			857	DC	XL16' 000000000000000012340565600C'	V1 source
00001498	00001234 0565600C			858			
				859 * VCVB simple: p2=1			
				860	VRR_I	VCVB, 9, 0	
000014A0		000014A0		861+	DS	OFD	
000014A0				862+	USING	*, R5	base for test data and test routine
000014A0	000014BC			863+T10	DC	A(X10)	address of test routine
000014A4	000A			864+	DC	H' 10'	test number
000014A6	00			865+	DC	XL1' 00'	
000014A7	09			866+	DC	HL1' 9'	&MB
000014A8	00			867+	DC	HL1' 0'	cc
000014A9	07			868+	DC	HL1' 7'	cc failed mask
000014AA	E5C3E5C2 40404040			869+	DC	CL8' VCVB'	instruction name
000014B4	00000010			870+	DC	A(16)	result length
000014B8	000014E0			871+REA10	DC	A(REA10)	result address
				872+*			INSTRUCTION UNDER TEST ROUTINE
000014BC				873+X10	DS	OF	
000014BC	E310 8EE8 0004		000010E8	874+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014C2	E710 5048 0006		000014E8	875+ VL	V1, RE10+8	get V1 source	
000014C8	E611 0090 0050			876+ VCVB	R1, V1, 9	test instruction	
000014CE	E310 8F20 0024		00001120	877+ STG	R1, R10OUTPUT	save	
000014D4	B98D 0020			878+ EPSW	R2, R0	extract psw	
000014D8	5020 8ED8		000010D8	879+ ST	R2, CCPSW	to save CC	
000014DC	07FB			880+ BR	R11	return	
000014E0				881+RE10 DC	OF		
000014E0				882+ DROP	R5		
000014E0	AABBCCDD 0000000A			883 DC	XL08' AABBCCDD0000000A'	R1 result	
000014E8	00000000 00000000			884 DC	XL16' 0000000000000000000000000000000010C'	V1 source	
000014F0	00000000 0000010C			885			
000014F8				886 VRR_I	VCVB, 9, 0		
000014F8	00001514	000014F8		887+ DS	OFD		
000014F8	000B			888+ USING	*, R5	base for test data and test routine	
000014FC				889+T11 DC	A(X11)	address of test routine	
000014FE	00			890+ DC	H' 11'	test number	
000014FF	09			891+ DC	XL1' 00'		
00001500	00			892+ DC	HL1' 9'	&MB	
00001501	07			893+ DC	HL1' 0'	cc	
00001502	E5C3E5C2 40404040			894+ DC	HL1' 7'	cc failed mask	
0000150C	00000010			895+ DC	CL8' VCVB'	instruction name	
00001510	00001538			896+ DC	A(16)	result length	
00001514				897+REA11 DC	A(RE11)	result address	
00001514	E310 8EE8 0004	000010E8		898+* DS	OF	INSTRUCTION UNDER TEST ROUTINE	
0000151A	E710 5048 0006	00001540		899+X11 LG	R1, R1FUDGE		
00001520	E611 0090 0050			900+ VL	V1, RE11+8	pollute R1	
00001526	E310 8F20 0024	00001120		901+ VCVB	R1, V1, 9	get V1 source	
0000152C	B98D 0020			902+ STG	R1, R10OUTPUT	test instruction	
00001530	5020 8ED8		000010D8	903+ EPSW	R2, R0	save	
00001534	07FB			904+ ST	R2, CCPSW	extract psw	
00001538				905+ BR	R11	to save CC	
00001538				906+ DC	OF	return	
00001538				907+RE11 DC	OF		
00001538				908+ DROP	R5		
00001538	AABBCCDD 0000000A			909 DC	XL08' AABBCCDD0000000A'	R1 result	
00001540	00000000 00000000			910 DC	XL16' 0000000000000000000000000000000010D'	V1 source	
00001548	00000000 0000010D			911			
00001550				912 VRR_I	VCVB, 9, 0		
00001550	0000156C	00001550		913+ DS	OFD		
00001550	0000156C			914+ USING	*, R5	base for test data and test routine	
00001554	000C			915+T12 DC	A(X12)	address of test routine	
00001556	00			916+ DC	H' 12'	test number	
00001557	09			917+ DC	XL1' 00'		
00001558	00			918+ DC	HL1' 9'	&MB	
00001559	07			919+ DC	HL1' 0'	cc	
0000155A	E5C3E5C2 40404040			920+ DC	HL1' 7'	cc failed mask	
00001564	00000010			921+ DC	CL8' VCVB'	instruction name	
00001568	00001590			922+ DC	A(16)	result length	
0000156C				923+REA12 DC	A(RE12)	result address	
0000156C	E310 8EE8 0004	000010E8		924+* DS	OF	INSTRUCTION UNDER TEST ROUTINE	
00001572	E710 5048 0006	00001598		926+ VL	R1, R1FUDGE		
00001578	E611 0090 0050			927+ VCVB	V1, RE12+8	pollute R1	
				928+ VCVB	R1, V1, 9	get V1 source	
						test instruction	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000157E	E310 8F20 0024		00001120	929+ 930+	STG EPSW	R1, R1OUTPUT R2, R0	save extract psw
00001584	B98D 0020		000010D8	931+ 932+ 933+RE12	ST BR DC	R2, CCPSW R11 OF	to save CC return
00001588	5020 8ED8			934+	DROP	R5	
0000158C	07FB			935	DC	XL08' AABBCCDD0008A160'	R1 result
00001590				936	DC	XL16' 00000000000000000000000000000000565600C'	V1 source
000015A0	00000000 0565600C			937 938	VRR_I	VCVB, 9, 0	
000015A8		000015A8		939+ 940+ 941+T13	DS USING DC	OFD *, R5 A(X13)	base for test data and test routine
000015A8	000015C4			942+ 943+ 944+ 945+ 946+ 947+	DC	H' 13' XL1' 00' HL1' 9' HL1' 0' HL1' 7' CL8' VCVB'	address of test routine test number
000015AC	000D			948+ 949+REA13	DC	A(16) A(RE13)	&M3
000015AE	00			950+*			cc
000015AF	09						cc failed mask
000015B0	00						instruction name
000015B1	07						result length
000015B2	E5C3E5C2 40404040						result address
000015BC	00000010						INSTRUCTION UNDER TEST ROUTINE
000015C0	000015E8						
000015C4				951+X13	DS	OF	
000015C4	E310 8EE8 0004		000010E8	952+ 953+	LG VL	R1, R1FUDGE V1, RE13+8	pollute R1 get V1 source
000015CA	E710 5048 0006		000015F0	954+	VCVB	R1, V1, 9	test instruction
000015D0	E611 0090 0050			955+ 956+	STG EPSW	R1, R1OUTPUT R2, R0	save extract psw
000015D6	E310 8F20 0024		00001120	957+ 958+	ST BR	R2, CCPSW R11	to save CC
000015DC	B98D 0020			959+REA13	DC	OF	return
000015E0	5020 8ED8		000010D8	960+ 961	DROP DC	R5 XL08' AABBCCDD0008A160'	
000015E4	07FB			962	DC	XL16' 00000000000000000000000000000000565600D'	R1 result V1 source
000015E8	AABBCCDD 0008A160			963 964	VRR_I	VCVB, 9, 0	INT_MAX
000015F0	00000000 00000000			965+ 966+ 967+T14	DS USING DC	OFD *, R5 A(X14)	base for test data and test routine
000015F8	00000000 0565600D			968+ 969+ 970+ 971+ 972+ 973+ 974+ 975+REA14	DC	H' 14' XL1' 00' HL1' 9' HL1' 0' HL1' 7' CL8' VCVB' A(16) A(RE14)	address of test routine test number
00001600		00001600		976+*			&M3
00001600	0000161C						cc
00001600	000E						cc failed mask
00001604	00						instruction name
00001606	09						result length
00001607	00						result address
00001608	07						INSTRUCTION UNDER TEST ROUTINE
0000160A	E5C3E5C2 40404040						
00001614	00000010						
00001618	00001640			977+X14	DS	OF	
0000161C	E310 8EE8 0004		000010E8	978+ 979+	LG VL	R1, R1FUDGE V1, RE14+8	pollute R1 get V1 source
00001622	E710 5048 0006		00001648	980+ 981+	VCVB STG	R1, V1, 9 R1, R1OUTPUT	test instruction save
00001628	E611 0090 0050		00001120	982+	EPSW	R2, R0	extract psw
0000162E	E310 8F20 0024						
00001634	B98D 0020						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001638	5020 8ED8		000010D8	983+ 984+ 985+RE14 986+ 987 988 989	ST BR DC DROP DC DC	R2, CCPSW R11 OF R5 XL08' AABBCCDD7FFFFFF' XL16' 000000000000000000000000000000002147483647C'	to save CC return R1 result V1 source INT_MIN
0000163C	07FB						
00001640							
00001640							
00001640	AABBCCDD 7FFFFFFF						
00001648	00000000 00000000						
00001650	00000214 7483647C						
00001658				990 991+ 992+ 993+T15 994+ 995+ 996+ 997+ 998+ 999+ 1000+ 1001+REA15 1002+*	VRR_I DS USING DC DC DC DC DC DC DC DC DC DC	VCVB, 9, 3 OFD *, R5 A(X15) H' 15' XL1' 00' HL1' 9' HL1' 3' HL1' 14' CL8' VCVB' A(16) A(REA15)	base for test data and test routine address of test routine test number &B cc cc failed mask instruction name result length result address INSTRUCTION UNDER TEST ROUTINE
00001658	00001674	00001658					
00001658	000F						
0000165E	00						
0000165F	09						
00001660	03						
00001661	0E						
00001662	E5C3E5C2 40404040						
0000166C	00000010						
00001670	00001698						
00001674	E310 8EE8 0004		000010E8	1003+X15 1004+ 1005+ 1006+ 1007+ 1008+ 1009+ 1010+	DS LG VL VCVB STG EPSW ST BR	OF R1, R1FUDGE V1, RE15+8 R1, V1, 9 R1, R1OUTPUT R2, R0 R2, CCPSW R11	pollute R1 get V1 source test instruction save extract psw to save CC return
00001674	E710 5048 0006		000016A0				
00001680	E611 0090 0050						
00001686	E310 8F20 0024		00001120				
0000168C	B98D 0020						
00001690	5020 8ED8		000010D8				
00001694	07FB						
00001698				1011+REA15 1012+ 1013 1014	DC DROP DC DC	OF R5 XL08' AABBCCDD80000000' XL16' 000000000000000000000000000000002147483648D'	R1 result V1 source
000016A0	AABBCCDD 80000000						
000016A8	00000000 00000000						
000016A8	00000214 7483648D						
000016B0				1015 1016 1017+ 1018+ 1019+T16 1020+ 1021+ 1022+ 1023+ 1024+ 1025+ 1026+ 1027+REA16 1028+*	VRR_I DS USING DC DC DC DC DC DC DC DC DC DC DC	VCVB, 11, 0 OFD *, R5 A(X16) H' 16' XL1' 00' HL1' 11' HL1' 0' HL1' 7' CL8' VCVB' A(16) A(REA16)	UINT_MAX base for test data and test routine address of test routine test number &B cc cc failed mask instruction name result length result address INSTRUCTION UNDER TEST ROUTINE
000016B0	000016CC	000016B0					
000016B4	0010						
000016B6	00						
000016B7	0B						
000016B8	00						
000016B9	07						
000016BA	E5C3E5C2 40404040						
000016C4	00000010						
000016C8	000016F0						
000016CC	E310 8EE8 0004		000010E8	1029+X16 1030+ 1031+ 1032+ 1033+ 1034+ 1035+ 1036+	DS LG VL VCVB STG EPSW ST BR	OF R1, R1FUDGE V1, RE16+8 R1, V1, 11 R1, R1OUTPUT R2, R0 R2, CCPSW R11	pollute R1 get V1 source test instruction save extract psw to save CC return
000016D2	E710 5048 0006		000016F8				
000016D8	E611 00B0 0050						
000016DE	E310 8F20 0024		00001120				
000016E4	B98D 0020						
000016E8	5020 8ED8		000010D8				
000016EC	07FB						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016F0				1037+RE16	DC	OF	
000016F0				1038+	DROP	R5	
000016F0	AABBCCDD FFFFFFFF			1039	DC	XL08' AABBCCDDFFFFFF'	R1 result
000016F8	00000000 00000000			1040	DC	XL16' 00000000000000004294967295C'	V1 source
00001700	00000429 4967295C			1041			
00001708				1042	VRR_I	VCVB, 11, 3	UINT_MAX +1
00001708				1043+	DS	OFD	
00001708	00001724	00001708		1044+	USING	*, R5	base for test data and test routine
00001708	0011			1045+T17	DC	A(X17)	address of test routine
0000170C				1046+	DC	H' 17'	test number
0000170E	00			1047+	DC	XL1' 00'	
0000170F	OB			1048+	DC	HL1' 11'	&MB
00001710	03			1049+	DC	HL1' 3'	cc
00001711	OE			1050+	DC	HL1' 14'	cc failed mask
00001712	E5C3E5C2 40404040			1051+	DC	CL8' VCVB'	instruction name
0000171C	00000010			1052+	DC	A(16)	result length
00001720	00001748			1053+REA17	DC	A(RE17)	result address
00001724				1054+*			INSTRUCTION UNDER TEST ROUTINE
00001724	1055+X17			DS	OF		
00001724	E310 8EE8 0004	000010E8		1056+	LG	R1, R1FUDGE	pollute R1
0000172A	E710 5048 0006	00001750		1057+	VL	V1, RE17+8	get V1 source
00001730	E611 00B0 0050			1058+	VCVB	R1, V1, 11	test instruction
00001736	E310 8F20 0024	00001120		1059+	STG	R1, R1OUTPUT	save
0000173C	B98D 0020			1060+	EPSW	R2, R0	extract psw
00001740	5020 8ED8	000010D8		1061+	ST	R2, CCPSW	to save CC
00001744	07FB			1062+	BR	R11	return
00001748				1063+REA17	DC	OF	
00001748				1064+	DROP	R5	
00001748	AABBCCDD 00000000			1065	DC	XL08' AABBCCDD00000000'	R1 result
00001750	00000000 00000000			1066	DC	XL16' 00000000000000004294967296C'	V1 source
00001758	00000429 4967296C			1067			
00001760				1068	VRR_I	VCVB, 9, 3	
00001760				1069+	DS	OFD	
00001760	0000177C	00001760		1070+	USING	*, R5	base for test data and test routine
00001760	0012			1071+T18	DC	A(X18)	address of test routine
00001764				1072+	DC	H' 18'	test number
00001766	00			1073+	DC	XL1' 00'	
00001767	09			1074+	DC	HL1' 9'	&MB
00001768	03			1075+	DC	HL1' 3'	cc
00001769	OE			1076+	DC	HL1' 14'	cc failed mask
0000176A	E5C3E5C2 40404040			1077+	DC	CL8' VCVB'	instruction name
00001774	00000010			1078+	DC	A(16)	result length
00001778	000017A0			1079+REA18	DC	A(RE18)	result address
0000177C				1080+*			INSTRUCTION UNDER TEST ROUTINE
0000177C	1081+X18			DS	OF		
0000177C	E310 8EE8 0004	000010E8		1082+	LG	R1, R1FUDGE	pollute R1
00001782	E710 5048 0006	000017A8		1083+	VL	V1, RE18+8	get V1 source
00001788	E611 0090 0050			1084+	VCVB	R1, V1, 9	test instruction
0000178E	E310 8F20 0024	00001120		1085+	STG	R1, R1OUTPUT	save
00001794	B98D 0020			1086+	EPSW	R2, R0	extract psw
00001798	5020 8ED8	000010D8		1087+	ST	R2, CCPSW	to save CC
0000179C	07FB			1088+	BR	R11	return
000017A0				1089+REA18	DC	OF	
000017A0				1090+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000017A0	AABBCCDD DF8E1660			1091 DC XL08' AABBCCDDDF8E1660'		R1 result
000017A8	00000000 00000000			1092 DC XL16' 0000000000000000000000000000000012340565600C'	V1 source	
000017B0	00001234 0565600C			1093		
				1094 *		
				1095 * VCVBG - VECTOR CONVERT TO BINARY (64)		
				1096 *		
				1097 * VCVBG simple		
000017B8				1098 VRR_I VCVBG, 1, 0		
000017B8		000017B8		1099+ DS OFD		
000017B8	000017D4			1100+ USING *, R5	base for test data and test routine	
000017BC	0013			1101+T19 DC A(X19)	address of test routine	
000017BE	00			1102+ DC H' 19'	test number	
000017BF	01			1103+ DC XL1' 00'		
000017C0	00			1104+ DC HL1' 1'	&MB	
000017C1	07			1105+ DC HL1' 0'	cc	
000017C2	E5C3E5C2 C7404040			1106+ DC HL1' 7'	cc failed mask	
000017CC	00000010			1107+ DC CL8' VCVBG'	instruction name	
000017D0	000017F8			1108+ DC A(16)	result length	
				1109+REA19 DC A(REA19)	result address	
				1110+*	INSTRUCTION UNDER TEST ROUTINE	
000017D4				1111+X19 DS OF		
000017D4	E310 8EE8 0004	000010E8		1112+ LG R1, R1FUDGE	pollute R1	
000017DA	E710 5048 0006	00001800		1113+ VL V1, RE19+8	get V1 source	
000017E0	E611 0010 0052			1114+ VCVBG R1, V1, 1	test instruction	
000017E6	E310 8F20 0024	00001120		1115+ STG R1, R1OUTPUT	save	
000017EC	B98D 0020			1116+ EPSW R2, R0	extract psw	
000017F0	5020 8ED8	000010D8		1117+ ST R2, CCPSW	to save CC	
000017F4	07FB			1118+ BR R11	return	
000017F8				1119+REA19 DC OF		
000017F8				1120+ DROP R5		
000017F8	00000000 0000000A			1121 DC XL08' 0000000000000000A'	R1 result	
00001800	00000000 00000000			1122 DC XL16' 0000000000000000000000000000000010C'	V1 source	
00001808	00000000 0000010C			1123		
00001810				1124 VRR_I VCVBG, 1, 0		
00001810		00001810		1125+ DS OFD		
00001810	0000182C			1126+ USING *, R5	base for test data and test routine	
00001814	0014			1127+T20 DC A(X20)	address of test routine	
00001816	00			1128+ DC H' 20'	test number	
00001817	01			1129+ DC XL1' 00'		
00001818	00			1130+ DC HL1' 1'	&MB	
00001819	07			1131+ DC HL1' 0'	cc	
0000181A	E5C3E5C2 C7404040			1132+ DC HL1' 7'	cc failed mask	
00001824	00000010			1133+ DC CL8' VCVBG'	instruction name	
00001828	00001850			1134+ DC A(16)	result length	
				1135+REA20 DC A(REA20)	result address	
				1136+*	INSTRUCTION UNDER TEST ROUTINE	
0000182C				1137+X20 DS OF		
0000182C	E310 8EE8 0004	000010E8		1138+ LG R1, R1FUDGE	pollute R1	
00001832	E710 5048 0006	00001858		1139+ VL V1, RE20+8	get V1 source	
00001838	E611 0010 0052			1140+ VCVBG R1, V1, 1	test instruction	
0000183E	E310 8F20 0024	00001120		1141+ STG R1, R1OUTPUT	save	
00001844	B98D 0020			1142+ EPSW R2, R0	extract psw	
00001848	5020 8ED8	000010D8		1143+ ST R2, CCPSW	to save CC	
0000184C	07FB			1144+ BR R11	return	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001850				1145+RE20	DC	OF	
00001850				1146+	DROP	R5	
00001850	FFFFFFFFFF FFFFFFF6			1147	DC	XL08' FFFFFFFFFFFFFF6'	R1 result
00001858	00000000 00000000			1148	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001860	00000000 0000010D			1149			
00001868				1150	VRR_I	VCVBG, 1, 0	
00001868	00001884	00001868		1151+	DS	OFD	
00001868	0015			1152+	USING	*, R5	base for test data and test routine
0000186C				1153+T21	DC	A(X21)	address of test routine
0000186E	00			1154+	DC	H' 21'	test number
0000186F	01			1155+	DC	XL1' 00'	
00001870	00			1156+	DC	HL1' 1'	&MB
00001871	07			1157+	DC	HL1' 0'	cc
00001872	E5C3E5C2 C7404040			1158+	DC	HL1' 7'	cc failed mask
0000187C	00000010			1159+	DC	CL8' VCVBG'	instruction name
00001880	000018A8			1160+	DC	A(16)	result length
00001884				1161+REA21	DC	A(RE21)	result address
00001884	E310 8EE8 0004	000010E8		1162+*			INSTRUCTION UNDER TEST ROUTINE
0000188A	E710 5048 0006	000018B0		1163+X21	DS	OF	
00001890	E611 0010 0052			1164+	LG	R1, R1FUDGE	pollute R1
00001896	E310 8F20 0024	00001120		1165+	VL	V1, RE21+8	get V1 source
0000189C	B98D 0020			1166+	VCVBG	R1, V1, 1	test instruction
000018A0	5020 8ED8	000010D8		1167+	STG	R1, R1OUTPUT	save
000018A4	07FB			1168+	EPSW	R2, R0	extract psw
000018A8				1169+	ST	R2, CCPSW	to save CC
000018A8	00000000 0008A160			1170+	BR	R11	return
000018B0	00000000 00000000			1171+REA21	DC	OF	
000018B8	00000000 0565600C			1172+	DROP	R5	
000018C0				1173	DC	XL08' 0000000000008A160'	R1 result
000018C0	000018DC	000018C0		1174	DC	XL16' 00000000000000000000000000000000565600C'	V1 source
000018C0	0016			1175			
000018C6	00			1176	VRR_I	VCVBG, 1, 0	
000018C7	01			1177+	DS	OFD	
000018C8	00			1178+	USING	*, R5	base for test data and test routine
000018C9	07			1179+T22	DC	A(X22)	address of test routine
000018CA	E5C3E5C2 C7404040			1180+	DC	H' 22'	test number
000018D4	00000010			1181+	DC	XL1' 00'	
000018D8	00001900			1182+	DC	HL1' 1'	&MB
000018DC				1183+	DC	HL1' 0'	cc
000018DC	E310 8EE8 0004	000010E8		1184+	DC	HL1' 7'	cc failed mask
000018E2	E710 5048 0006	00001908		1185+	DC	CL8' VCVBG'	instruction name
000018E8	E611 0010 0052			1186+	DC	A(16)	result length
000018EE	E310 8F20 0024	00001120		1187+REA22	DC	A(RE22)	result address
000018F4	B98D 0020			1188+*			INSTRUCTION UNDER TEST ROUTINE
000018F8	5020 8ED8	000010D8		1189+X22	DS	OF	
000018FC	07FB			1190+	LG	R1, R1FUDGE	pollute R1
00001900				1191+	VL	V1, RE22+8	get V1 source
00001900				1192+	VCVBG	R1, V1, 1	test instruction
00001900				1193+	STG	R1, R1OUTPUT	save
00001900				1194+	EPSW	R2, R0	extract psw
00001900				1195+	ST	R2, CCPSW	to save CC
00001900				1196+	BR	R11	return
00001900				1197+RE22	DC	OF	
00001900				1198+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001900	FFFFFFF FFF75EA0			1199	DC	XL08' FFFFFFFF75EA0'	R1 result
00001908	00000000 00000000			1200	DC	XL16' 00000000000000000000000000000000565600D'	V1 source
00001910	00000000 0565600D			1201			
				1202	VRR_I	VCVBG, 1, 0	INT_MAX
00001918				1203+	DS	OFD	
00001918		00001918		1204+	USING	*, R5	base for test data and test routine
00001918	00001934			1205+T23	DC	A(X23)	address of test routine
0000191C	0017			1206+	DC	H' 23'	test number
0000191E	00			1207+	DC	XL1' 00'	
0000191F	01			1208+	DC	HL1' 1'	&MB
00001920	00			1209+	DC	HL1' 0'	cc
00001921	07			1210+	DC	HL1' 7'	cc failed mask
00001922	E5C3E5C2 C7404040			1211+	DC	CL8' VCVBG'	instruction name
0000192C	00000010			1212+	DC	A(16)	result length
00001930	00001958			1213+REA23	DC	A(REA23)	result address
				1214+*			INSTRUCTION UNDER TEST ROUTINE
00001934				1215+X23	DS	OF	
00001934	E310 8EE8 0004		000010E8	1216+	LG	R1, R1FUDGE	pollute R1
0000193A	E710 5048 0006		00001960	1217+	VL	V1, RE23+8	get V1 source
00001940	E611 0010 0052			1218+	VCVBG	R1, V1, 1	test instruction
00001946	E310 8F20 0024		00001120	1219+	STG	R1, R1OUTPUT	save
0000194C	B98D 0020			1220+	EPSW	R2, R0	extract psw
00001950	5020 8ED8		000010D8	1221+	ST	R2, CCPSW	
00001954	07FB			1222+	BR	R11	to save CC
00001958				1223+RE23	DC	OF	return
00001958				1224+	DROP	R5	
00001958	00000000 7FFFFFFF			1225	DC	XL08' 000000007FFFFFFF'	R1 result
00001960	00000000 00000000			1226	DC	XL16' 000000000000000000000000000000002147483647C'	V1 source
00001968	00000214 7483647C			1227			
				1228	VRR_I	VCVBG, 1, 0	INT_MIN
00001970				1229+	DS	OFD	
00001970		00001970		1230+	USING	*, R5	base for test data and test routine
00001970	0000198C			1231+T24	DC	A(X24)	address of test routine
00001974	0018			1232+	DC	H' 24'	test number
00001976	00			1233+	DC	XL1' 00'	
00001977	01			1234+	DC	HL1' 1'	&MB
00001978	00			1235+	DC	HL1' 0'	cc
00001979	07			1236+	DC	HL1' 7'	cc failed mask
0000197A	E5C3E5C2 C7404040			1237+	DC	CL8' VCVBG'	instruction name
00001984	00000010			1238+	DC	A(16)	result length
00001988	000019B0			1239+REA24	DC	A(REA24)	result address
				1240+*			INSTRUCTION UNDER TEST ROUTINE
0000198C				1241+X24	DS	OF	
0000198C	E310 8EE8 0004		000010E8	1242+	LG	R1, R1FUDGE	pollute R1
00001992	E710 5048 0006		000019B8	1243+	VL	V1, RE24+8	get V1 source
00001998	E611 0010 0052			1244+	VCVBG	R1, V1, 1	test instruction
0000199E	E310 8F20 0024		00001120	1245+	STG	R1, R1OUTPUT	save
000019A4	B98D 0020			1246+	EPSW	R2, R0	extract psw
000019A8	5020 8ED8		000010D8	1247+	ST	R2, CCPSW	
000019AC	07FB			1248+	BR	R11	to save CC
000019B0				1249+RE24	DC	OF	return
000019B0				1250+	DROP	R5	
000019B0	FFFFFFF 80000000			1251	DC	XL08' FFFFFFF80000000'	R1 result
000019B8	00000000 00000000			1252	DC	XL16' 000000000000000000000000000000002147483648D'	V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019C0	00000214 7483648D			1253		
000019C8				1254	VRR_I VCVBG, 1, 0	UINT_MAX
000019C8				1255+	DS OFD	
000019C8		000019C8		1256+	USING *, R5	base for test data and test routine
000019C8	000019E4			1257+T25	DC A(X25)	address of test routine
000019CC	0019			1258+	DC H'25'	test number
000019CE	00			1259+	DC XL1'00'	
000019CF	01			1260+	DC HL1'1'	&MB
000019D0	00			1261+	DC HL1'0'	cc
000019D1	07			1262+	DC HL1'7'	cc failed mask
000019D2	E5C3E5C2 C7404040			1263+	DC CL8'VCVBG'	instruction name
000019DC	00000010			1264+	DC A(16)	result length
000019EO	00001A08			1265+REA25	DC A(REA25)	result address
000019E4				1266+*		INSTRUCTION UNDER TEST ROUTINE
000019E4	E310 8EE8 0004		000010E8	1267+X25	DS OF	
000019EA	E710 5048 0006		00001A10	1268+	LG R1, R1FUDGE	pollute R1
000019F0	E611 0010 0052			1269+	VL V1, RE25+8	get V1 source
000019F6	E310 8F20 0024		00001120	1270+	VCVBG R1, V1, 1	test instruction
000019FC	B98D 0020			1271+	STG R1, R1OUTPUT	save
00001A00	5020 8ED8		000010D8	1272+	EPSW R2, R0	extract psw
00001A04	07FB			1273+	ST R2, CCPSW	to save CC
00001A04				1274+	BR R11	return
00001A08				1275+RE25	DC OF	
00001A08				1276+	DROP R5	
00001A08	00000000 FFFFFFFF			1277	DC XL08'00000000FFFFFFFFFF'	R1 result
00001A10	00000000 00000000			1278	DC XL16'0000000000000000000000004294967295C'	V1 source
00001A18	00000429 4967295C			1279		
00001A20				1280	VRR_I VCVBG, 1, 0	UINT_MAX +1
00001A20				1281+	DS OFD	
00001A20	00001A20			1282+	USING *, R5	base for test data and test routine
00001A20	00001A3C			1283+T26	DC A(X26)	address of test routine
00001A24	001A			1284+	DC H'26'	test number
00001A26	00			1285+	DC XL1'00'	
00001A27	01			1286+	DC HL1'1'	&MB
00001A28	00			1287+	DC HL1'0'	cc
00001A29	07			1288+	DC HL1'7'	cc failed mask
00001A2A	E5C3E5C2 C7404040			1289+	DC CL8'VCVBG'	instruction name
00001A34	00000010			1290+	DC A(16)	result length
00001A38	00001A60			1291+REA26	DC A(REA26)	result address
00001A3C				1292+*		INSTRUCTION UNDER TEST ROUTINE
00001A3C	E310 8EE8 0004		000010E8	1293+X26	DS OF	
00001A42	E710 5048 0006		00001A68	1294+	LG R1, R1FUDGE	pollute R1
00001A48	E611 0010 0052			1295+	VL V1, RE26+8	get V1 source
00001A4E	E310 8F20 0024		00001120	1296+	VCVBG R1, V1, 1	test instruction
00001A54	B98D 0020			1297+	STG R1, R1OUTPUT	save
00001A58	5020 8ED8		000010D8	1298+	EPSW R2, R0	extract psw
00001A5C	07FB			1299+	ST R2, CCPSW	to save CC
00001A60				1300+	BR R11	return
00001A60				1301+RE26	DC OF	
00001A60				1302+	DROP R5	
00001A60	00000001 00000000			1303	DC XL08'0000000100000000'	R1 result
00001A68	00000000 00000000			1304	DC XL16'0000000000000000000000004294967296C'	V1 source
00001A70	00000429 4967296C			1305		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A78				1306 1307+	VRR_I VCVBG, 1, 0 DS OFD		
00001A78	00001A94	00001A78		1308+ 1309+T27 1310+	USING *, R5 DC A(X27) DC H' 27'	base for test data and test routine address of test routine test number	
00001A7C	001B			1311+ 1312+ 1313+	DC XL1' 00' DC HL1' 1' DC HL1' 0'	&M cc	
00001A7E	00			1314+ 1315+ 1316+	DC HL1' 7' DC CL8' VCVBG' DC A(16)	cc failed mask instruction name result length	
00001A80	00			1317+RE27 1318+*	DC A(RE27)	result address	
00001A81	07			1319+X27	DS OF	INSTRUCTION UNDER TEST ROUTINE	
00001A82	E5C3E5C2 C7404040			1320+ 1321+ 1322+	LG R1, R1FUDGE VL V1, RE27+8 VCVBG R1, V1, 1	pollute R1 get V1 source test instruction	
00001A8C	00000010			1323+ 1324+ 1325+	STG R1, R1OUTPUT EPSW R2, RO ST R2, CCPSW	save extract psw to save CC	
00001A90	00001AB8			1326+ 1327+RE27 1328+	BR R11 DC OF DROP R5	return	
00001AB4	07FB			1329	DC XL08' 00000002DF8E1660'	R1 result	
00001AB8	00000002 DF8E1660			1330	DC XL16' 0000000000000000000012340565600C'	V1 source	
00001AC8	00001234 0565600C			1331 1332 1333+	VRR_I VCVBG, 1, 0 DS OFD	LONG_MAX	
00001AD0		00001AD0		1334+ 1335+T28 1336+	USING *, R5 DC A(X28) DC H' 28'	base for test data and test routine address of test routine test number	
00001AD0	00001AEC			1337+ 1338+ 1339+	DC XL1' 00' DC HL1' 1' DC HL1' 0'	&M cc	
00001AD4	001C			1340+ 1341+ 1342+	DC HL1' 7' DC CL8' VCVBG' DC A(16)	cc failed mask instruction name result length	
00001AD6	00			1343+RE28 1344+*	DC A(RE28)	result address	
00001AD7	01			1345+X28	DS OF	INSTRUCTION UNDER TEST ROUTINE	
00001AD8	00			1346+ 1347+ 1348+	LG R1, R1FUDGE VL V1, RE28+8 VCVBG R1, V1, 1	pollute R1 get V1 source test instruction	
00001AD9	07			1349+ 1350+ 1351+	STG R1, R1OUTPUT EPSW R2, RO ST R2, CCPSW	save extract psw to save CC	
00001ADA	E5C3E5C2 C7404040			1352+ 1353+RE28 1354+	BR R11 DC OF DROP R5	return	
00001AE4	00000010			1355	DC XL08' 7FFFFFFFFFFFF'	R1 result	
00001AE8	00001B10			1356	DC XL16' 0000000000009223372036854775807C'	V1 source	
00001AEC	E310 8EE8 0004	000010E8		1357 1358 1359+	VRR_I VCVBG, 1, 0 DS OFD	LONG_MIN	
00001AF2	E710 5048 0006	00001B18					
00001AF8	E611 0010 0052						
00001AFE	E310 8F20 0024	00001120					
00001B04	B98D 0020						
00001B08	5020 8ED8	000010D8					
00001BOC	07FB						
00001B10	7FFFFFF FFFFFFF						
00001B18	00000000 00009223						
00001B20	37203685 4775807C						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B28		00001B28		1360+ USING *, R5	base for test data and test routine	
00001B28	00001B44			1361+T29 DC A(X29)	address of test routine	
00001B2C	001D			1362+ DC H'29'	test number	
00001B2E	00			1363+ DC XL1'00'		
00001B2F	01			1364+ DC HL1'1'	&MB	
00001B30	00			1365+ DC HL1'0'	cc	
00001B31	07			1366+ DC HL1'7'	cc failed mask	
00001B32	E5C3E5C2 C7404040			1367+ DC CL8'VCVBG'	instruction name	
00001B3C	00000010			1368+ DC A(16)	result length	
00001B40	00001B68			1369+REA29 DC A(RE29)	result address	
				1370+*	INSTRUCTION UNDER TEST ROUTINE	
00001B44				1371+X29 DS OF		
00001B44	E310 8EE8 0004		000010E8	1372+ LG R1, R1FUDGE	pollute R1	
00001B4A	E710 5048 0006		00001B70	1373+ VL V1, RE29+8	get V1 source	
00001B50	E611 0010 0052			1374+ VCVBG R1, V1, 1	test instruction	
00001B56	E310 8F20 0024		00001120	1375+ STG R1, R1OUTPUT	save	
00001B5C	B98D 0020			1376+ EPSW R2, R0	extract psw	
00001B60	5020 8ED8		000010D8	1377+ ST R2, CCPSW	to save CC	
00001B64	07FB			1378+ BR R11	return	
00001B68				1379+REA29 DC OF		
00001B68				1380+ DROP R5		
00001B68	80000000 00000000			1381 DC XL08'8000000000000000'	R1 result	
00001B70	00000000 00009223			1382 DC XL16'0000000000009223372036854775808D'	V1 source	
00001B78	37203685 4775808D			1383	ULONG_MAX	
00001B80				1384 VRR_I VCVBG, 3, 0		
00001B80		00001B80		1385+ DS OFD		
00001B80	00001B9C			1386+ USING *, R5	base for test data and test routine	
				1387+T30 DC A(X30)	address of test routine	
00001B84	001E			1388+ DC H'30'	test number	
00001B86	00			1389+ DC XL1'00'		
00001B87	03			1390+ DC HL1'3'	&MB	
00001B88	00			1391+ DC HL1'0'	cc	
00001B89	07			1392+ DC HL1'7'	cc failed mask	
00001B8A	E5C3E5C2 C7404040			1393+ DC CL8'VCVBG'	instruction name	
00001B94	00000010			1394+ DC A(16)	result length	
00001B98	00001BC0			1395+REA30 DC A(RE30)	result address	
				1396+*	INSTRUCTION UNDER TEST ROUTINE	
00001B9C				1397+X30 DS OF		
00001B9C	E310 8EE8 0004		000010E8	1398+ LG R1, R1FUDGE	pollute R1	
00001BA2	E710 5048 0006		00001BC8	1399+ VL V1, RE30+8	get V1 source	
00001BA8	E611 0030 0052			1400+ VCVBG R1, V1, 3	test instruction	
00001BAE	E310 8F20 0024		00001120	1401+ STG R1, R1OUTPUT	save	
00001BB4	B98D 0020			1402+ EPSW R2, R0	extract psw	
00001BB8	5020 8ED8		000010D8	1403+ ST R2, CCPSW	to save CC	
00001BBC	07FB			1404+ BR R11	return	
00001BC0				1405+REA30 DC OF		
00001BC0	FFFFFFFF FFFFFFFF			1406+ DROP R5		
00001BC8	00000000 00018446			1407 DC XL08'FFFFFFFFFFFF'	R1 result	
00001BD0	74407370 9551615C			1408 DC XL16'00000000000018446744073709551615C'	V1 source	
00001BD8				1409 VRR_I VCVBG, 3, 3	ULONG_MAX +1	
00001BD8				1410 DS OFD		
00001BD8	00001BF4	00001BD8		1411+ USING *, R5	base for test data and test routine	
				1412+ DC A(X31)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STM		
00001BDC	001F			1414+	DC	H' 31'
00001BDE	00			1415+	DC	XL1' 00'
00001BDF	03			1416+	DC	HL1' 3'
00001BEO	03			1417+	DC	HL1' 3'
00001BE1	0E			1418+	DC	HL1' 14'
00001BE2	E5C3E5C2 C7404040			1419+	DC	CL8' VCVBG'
00001BEC	00000010			1420+	DC	A(16)
00001BF0	00001C18			1421+REA31	DC	A(RE31)
				1422+*		
00001BF4				1423+X31	DS	OF
00001BF4	E310 8EE8 0004	000010E8		1424+	LG	R1, R1FUDGE
00001BFA	E710 5048 0006	00001C20		1425+	VL	V1, RE31+8
00001C00	E611 0030 0052	00001120		1426+	VCVBG	R1, V1, 3
00001C06	E310 8F20 0024	00001120		1427+	STG	R1, R1OUTPUT
00001COC	B98D 0020			1428+	EPSW	R2, R0
00001C10	5020 8ED8	000010D8		1429+	ST	R2, CCPSW
00001C14	07FB			1430+	BR	R11
00001C18				1431+RE31	DC	OF
00001C18				1432+	DROP	R5
00001C18	00000000 00000000			1433	DC	XL08' 0000000000000000'
00001C20	00000000 00018446			1434	DC	XL16' 000000000018446744073709551616C'
00001C28	74407370 9551616C			1435		
				1436	VRR_I	VCVBG, 3, 3
00001C30		00001C30		1437+	DS	OFD
00001C30				1438+	USING	* , R5
00001C30	00001C4C			1439+T32	DC	A(X32)
00001C34	0020			1440+	DC	H' 32'
00001C36	00			1441+	DC	XL1' 00'
00001C37	03			1442+	DC	HL1' 3'
00001C38	03			1443+	DC	HL1' 3'
00001C39	0E			1444+	DC	HL1' 14'
00001C3A	E5C3E5C2 C7404040			1445+	DC	CL8' VCVBG'
00001C44	00000010			1446+	DC	A(16)
00001C48	00001C70			1447+REA32	DC	A(RE32)
				1448+*		
00001C4C				1449+X32	DS	OF
00001C4C	E310 8EE8 0004	000010E8		1450+	LG	R1, R1FUDGE
00001C52	E710 5048 0006	00001C78		1451+	VL	V1, RE32+8
00001C58	E611 0030 0052	00001120		1452+	VCVBG	R1, V1, 3
00001C5E	E310 8F20 0024	00001120		1453+	STG	R1, R1OUTPUT
00001C64	B98D 0020			1454+	EPSW	R2, R0
00001C68	5020 8ED8	000010D8		1455+	ST	R2, CCPSW
00001C6C	07FB			1456+	BR	R11
00001C70				1457+RE32	DC	OF
00001C70				1458+	DROP	R5
00001C70	00000000 0000000A			1459	DC	XL08' 000000000000000A'
00001C78	00000000 00018446			1460	DC	XL16' 000000000018446744073709551626C'
00001C80	74407370 9551626C			1461		
				1462 * VCVBG simple: p2=1		
00001C88		00001C88		1463	VRR_I	VCVBG, 9, 0
00001C88	00001CA4			1464+	DS	OFD
00001C88	0021			1465+	USING	* , R5
00001C88				1466+T33	DC	A(X33)
00001C8C				1467+	DC	H' 33'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001C8E	00			1468+	DC	XL1' 00'
00001C8F	09			1469+	DC	HL1' 9'
00001C90	00			1470+	DC	HL1' 0'
00001C91	07			1471+	DC	HL1' 7'
00001C92	E5C3E5C2 C7404040			1472+	DC	CL8' VCVBG'
00001C9C	00000010			1473+	DC	A(16)
00001CA0	00001CC8			1474+REA33	DC	A(REA33)
				1475+*		
00001CA4				1476+X33	DS	OF
00001CA4	E310 8EE8 0004		000010E8	1477+	LG	R1, R1FUDGE
00001CAA	E710 5048 0006		00001CD0	1478+	VL	V1, RE33+8
00001CB0	E611 0090 0052			1479+	VCVBG	R1, V1, 9
00001CB6	E310 8F20 0024		00001120	1480+	STG	R1, R1OUTPUT
00001CBC	B98D 0020			1481+	EPSW	R2, R0
00001CC0	5020 8ED8		000010D8	1482+	ST	R2, CCPSW
00001CC4	07FB			1483+	BR	R11
00001CC8				1484+RE33	DC	OF
00001CC8				1485+	DROP	R5
00001CC8	00000000 0000000A			1486	DC	XL08' 0000000000000000A'
00001CD0	00000000 00000000			1487	DC	XL16' 0000000000000000000000000000000010C'
00001CD8	00000000 0000010C					R1 result V1 source
				1488		
				1489	VRR_I	VCVBG, 9, 0
00001CE0				1490+	DS	OFD
00001CE0		00001CEO		1491+	USING	*, R5
00001CE0	00001CFC			1492+T34	DC	A(X34)
00001CE4	0022			1493+	DC	H' 34'
00001CE6	00			1494+	DC	XL1' 00'
00001CE7	09			1495+	DC	HL1' 9'
00001CE8	00			1496+	DC	HL1' 0'
00001CE9	07			1497+	DC	HL1' 7'
00001CEA	E5C3E5C2 C7404040			1498+	DC	CL8' VCVBG'
00001CF4	00000010			1499+	DC	A(16)
00001CF8	00001D20			1500+REA34	DC	A(REA34)
				1501+*		
00001CFC				1502+X34	DS	OF
00001CFC	E310 8EE8 0004		000010E8	1503+	LG	R1, R1FUDGE
00001D02	E710 5048 0006		00001D28	1504+	VL	V1, RE34+8
00001D08	E611 0090 0052			1505+	VCVBG	R1, V1, 9
00001D0E	E310 8F20 0024		00001120	1506+	STG	R1, R1OUTPUT
00001D14	B98D 0020			1507+	EPSW	R2, R0
00001D18	5020 8ED8		000010D8	1508+	ST	R2, CCPSW
00001D1C	07FB			1509+	BR	R11
00001D20				1510+RE34	DC	OF
00001D20				1511+	DROP	R5
00001D20	00000000 0000000A			1512	DC	XL08' 0000000000000000A'
00001D28	00000000 00000000			1513	DC	XL16' 0000000000000000000000000000000010D'
00001D30	00000000 0000010D					R1 result V1 source
				1514		
				1515	VRR_I	VCVBG, 9, 0
00001D38				1516+	DS	OFD
00001D38		00001D38		1517+	USING	*, R5
00001D38	00001D54			1518+T35	DC	A(X35)
00001D3C	0023			1519+	DC	H' 35'
00001D3E	00			1520+	DC	XL1' 00'
00001D3F	09			1521+	DC	HL1' 9'
						&MB

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001D40	00			1522+	DC	HL1' 0'
00001D41	07			1523+	DC	HL1' 7'
00001D42	E5C3E5C2 C7404040			1524+	DC	CL8' VCVBG'
00001D4C	00000010			1525+	DC	A(16)
00001D50	00001D78			1526+REA35	DC	A(RE35)
				1527+*		cc failed mask
00001D54				1528+X35	DS	OF
00001D54	E310 8EE8 0004	000010E8	1529+	LG	R1, R1FUDGE	instruction name
00001D5A	E710 5048 0006	00001D80	1530+	VL	V1, RE35+8	result length
00001D60	E611 0090 0052		1531+	VCVBG	R1, V1, 9	result address
00001D66	E310 8F20 0024	00001120	1532+	STG	R1, R1OUTPUT	INSTRUCTION UNDER TEST ROUTINE
00001D6C	B98D 0020		1533+	EPSW	R2, R0	pollute R1
00001D70	5020 8ED8	000010D8	1534+	ST	R2, CCPSW	get V1 source
00001D74	07FB		1535+	BR	R11	test instruction
00001D78			1536+RE35	DC	OF	save
00001D78			1537+	DROP	R5	extract psw
00001D78	00000000 0008A160		1538	DC	XL08' 0000000000008A160'	to save CC
00001D80	00000000 00000000		1539	DC	XL16' 00000000000000000000000000000000565600C'	return
00001D88	00000000 0565600C			1540		R1 result
				1541	VRR_I	VCVBG, 9, 0
00001D90		00001D90	1542+	DS	OFD	V1 source
00001D90			1543+	USING	*, R5	base for test data and test routine
00001D90	00001DAC		1544+T36	DC	A(X36)	address of test routine
00001D94	0024		1545+	DC	H' 36'	test number
00001D96	00		1546+	DC	XL1' 00'	&MB
00001D97	09		1547+	DC	HL1' 9'	cc
00001D98	00		1548+	DC	HL1' 0'	cc failed mask
00001D99	07		1549+	DC	HL1' 7'	instruction name
00001D9A	E5C3E5C2 C7404040		1550+	DC	CL8' VCVBG'	result length
00001DA4	00000010		1551+	DC	A(16)	result address
00001DA8	00001DD0		1552+REA36	DC	A(RE36)	INSTRUCTION UNDER TEST ROUTINE
			1553+*			pollute R1
00001DAC			1554+X36	DS	OF	get V1 source
00001DAC	E310 8EE8 0004	000010E8	1555+	LG	R1, R1FUDGE	test instruction
00001DB2	E710 5048 0006	00001DD8	1556+	VL	V1, RE36+8	save
00001DB8	E611 0090 0052		1557+	VCVBG	R1, V1, 9	extract psw
00001DBE	E310 8F20 0024	00001120	1558+	STG	R1, R1OUTPUT	to save CC
00001DC4	B98D 0020		1559+	EPSW	R2, R0	return
00001DC8	5020 8ED8	000010D8	1560+	ST	R2, CCPSW	
00001DCC	07FB		1561+	BR	R11	
00001DD0			1562+RE36	DC	OF	
00001DD0			1563+	DROP	R5	
00001DD0	00000000 0008A160		1564	DC	XL08' 0000000000008A160'	R1 result
00001DD8	00000000 00000000		1565	DC	XL16' 00000000000000000000000000000000565600D'	V1 source
			1566			INT_MAX
00001DE8		00001DE8	1567	VRR_I	VCVBG, 9, 0	
00001DE8			1568+	DS	OFD	base for test data and test routine
00001DE8	00001E04		1569+	USING	*, R5	address of test routine
00001DEC	0025		1570+T37	DC	A(X37)	test number
00001DEE	00		1571+	DC	H' 37'	&MB
00001DEF	09		1572+	DC	XL1' 00'	cc
00001DF0	00		1573+	DC	HL1' 9'	cc failed mask
00001DF1	07		1574+	DC	HL1' 0'	
			1575+	DC	HL1' 7'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DF2	E5C3E5C2 C7404040			1576+ DC CL8' VCVBG'	instruction name		
00001DFC	00000010			1577+ DC A(16)	result length		
00001E00	00001E28			1578+REA37 DC A(REA37)	result address		
				1579+* 1580+X37 DS OF	INSTRUCTION UNDER TEST ROUTINE		
00001E04				1581+ LG R1, R1FUDGE			
00001E04	E310 8EE8 0004	000010E8		1582+ VL V1, RE37+8	pollute R1		
00001E0A	E710 5048 0006	00001E30		1583+ VCVBG R1, V1, 9	get V1 source		
00001E10	E611 0090 0052			1584+ STG R1, R1OUTPUT	test instruction		
00001E16	E310 8F20 0024	00001120		1585+ EPSW R2, R0	save		
00001E1C	B98D 0020			1586+ ST R2, CCPSW	extract psw		
00001E20	5020 8ED8	000010D8		1587+ BR R11	to save CC		
00001E24	07FB			1588+REA37 DC OF	return		
00001E28				1589+ DROP R5			
00001E28	00000000 7FFFFFFF			1590 DC XL08' 000000007FFFFFFF'	R1 result		
00001E30	00000000 00000000			1591 DC XL16' 000000000000000000000000000000002147483647C'	V1 source		
00001E38	00000214 7483647C			1592			
				1593 VRR_I VCVBG, 9, 0	INT_MIN		
				1594+ DS OFD			
00001E40		00001E40		1595+ USING *, R5	base for test data and test routine		
00001E40	00001E5C			1596+T38 DC A(X38)	address of test routine		
00001E44	0026			1597+ DC H' 38'	test number		
00001E46	00			1598+ DC XL1' 00'			
00001E47	09			1599+ DC HL1' 9'	&MB		
00001E48	00			1600+ DC HL1' 0'	cc		
00001E49	07			1601+ DC HL1' 7'	cc failed mask		
00001E4A	E5C3E5C2 C7404040			1602+ DC CL8' VCVBG'	instruction name		
00001E54	00000010			1603+ DC A(16)	result length		
00001E58	00001E80			1604+REA38 DC A(REA38)	result address		
				1605+*	INSTRUCTION UNDER TEST ROUTINE		
				1606+X38 DS OF			
00001E5C				1607+ LG R1, R1FUDGE	pollute R1		
00001E5C	E310 8EE8 0004	000010E8		1608+ VL V1, RE38+8	get V1 source		
00001E62	E710 5048 0006	00001E88		1609+ VCVBG R1, V1, 9	test instruction		
00001E68	E611 0090 0052			1610+ STG R1, R1OUTPUT	save		
00001E6E	E310 8F20 0024	00001120		1611+ EPSW R2, R0	extract psw		
00001E74	B98D 0020			1612+ ST R2, CCPSW	to save CC		
00001E78	5020 8ED8	000010D8		1613+ BR R11	return		
00001E7C	07FB			1614+REA38 DC OF			
00001E80				1615+ DROP R5			
00001E80	00000000 80000000			1616 DC XL08' 0000000080000000'	R1 result		
00001E88	00000000 00000000			1617 DC XL16' 000000000000000000000000000000002147483648D'	V1 source		
00001E90	00000214 7483648D			1618			
				1619 VRR_I VCVBG, 9, 0	UINT_MAX		
				1620+ DS OFD			
00001E98		00001E98		1621+ USING *, R5	base for test data and test routine		
00001E98	00001EB4			1622+T39 DC A(X39)	address of test routine		
00001E9C	0027			1623+ DC H' 39'	test number		
00001E9E	00			1624+ DC XL1' 00'			
00001E9F	09			1625+ DC HL1' 9'	&MB		
00001EA0	00			1626+ DC HL1' 0'	cc		
00001EA1	07			1627+ DC HL1' 7'	cc failed mask		
00001EA2	E5C3E5C2 C7404040			1628+ DC CL8' VCVBG'	instruction name		
00001EAC	00000010			1629+ DC A(16)	result length		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001EB0	00001ED8			1630+REA39 1631+*	DC	A(REA39)	result address INSTRUCTION UNDER TEST ROUTINE
00001EB4	E310 8EE8 0004			1632+X39	DS	OF	
00001EB4	E710 5048 0006	00001E8	00001EE0	1633+ 1634+	LG VL	R1, R1FUDGE V1, RE39+8	pollute R1 get V1 source
00001EC0	E611 0090 0052			1635+	VCVBG	R1, V1, 9	test instruction
00001EC6	E310 8F20 0024		00001120	1636+	STG	R1, R1OUTPUT	save
00001ECC	B98D 0020			1637+	EPSW	R2, R0	extract psw
00001ED0	5020 8ED8		000010D8	1638+ 1639+ 1640+RE39	ST BR DC	R2, CCPSW R11 OF	to save CC return
00001ED4	07FB			1641+	DROP	R5	
00001ED8	00000000 FFFFFFFF			1642	DC	XL08' 00000000FFFFFFFFFF'	R1 result
00001EE0	00000000 00000000			1643	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001EE8	00000429 4967295C			1644 1645	VRR_I	VCVBG, 9, 0	UINT_MAX +1
00001EF0	00001FOC	00001EF0		1646+ 1647+ 1648+T40	DS USING DC	OFD *, R5 A(X40)	base for test data and test routine address of test routine
00001EF4	0028			1649+	DC	H' 40'	test number
00001EF6	00			1650+	DC	XL1' 00'	
00001EF7	09			1651+	DC	HL1' 9'	&MB
00001EF8	00			1652+	DC	HL1' 0'	cc
00001EF9	07			1653+	DC	HL1' 7'	cc failed mask
00001EFA	E5C3E5C2 C7404040			1654+	DC	CL8' VCVBG'	instruction name
00001F04	00000010			1655+	DC	A(16)	result length
00001F08	00001F30			1656+REA40 1657+*	DC	A(REA40)	result address
00001F0C	E310 8EE8 0004		000010E8	1658+X40	DS	OF	INSTRUCTION UNDER TEST ROUTINE
00001F12	E710 5048 0006		00001F38	1659+ 1660+	LG VL	R1, R1FUDGE V1, RE40+8	pollute R1 get V1 source
00001F18	E611 0090 0052			1661+	VCVBG	R1, V1, 9	test instruction
00001F1E	E310 8F20 0024		00001120	1662+	STG	R1, R1OUTPUT	save
00001F24	B98D 0020			1663+	EPSW	R2, R0	extract psw
00001F28	5020 8ED8		000010D8	1664+ 1665+ 1666+RE40	ST BR DC	R2, CCPSW R11 OF	to save CC return
00001F30	00000001 00000000			1667+	DROP	R5	
00001F38	00000000 00000000			1668	DC	XL08' 0000000100000000'	R1 result
00001F40	00000429 4967296C			1669	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001F48	00001F64	00001F48		1670 1671	VRR_I	VCVBG, 9, 0	
00001F48	0029			1672+ 1673+ 1674+T41	DS USING DC	OFD *, R5 A(X41)	base for test data and test routine address of test routine
00001F4E	00			1675+	DC	H' 41'	test number
00001F4F	09			1676+ 1677+	DC	XL1' 00' HL1' 9'	&MB
00001F50	00			1678+	DC	HL1' 0'	cc
00001F51	07			1679+	DC	HL1' 7'	cc failed mask
00001F52	E5C3E5C2 C7404040			1680+	DC	CL8' VCVBG'	instruction name
00001F5C	00000010			1681+	DC	A(16)	result length
00001F60	00001F88			1682+REA41 1683+*	DC	A(REA41)	result address
							INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F64				1684+X41	DS	OF	
00001F64	E310 8EE8 0004		000010E8	1685+	LG	R1, R1FUDGE	pollute R1
00001F6A	E710 5048 0006		00001F90	1686+	VL	V1, RE41+8	get V1 source
00001F70	E611 0090 0052			1687+	VCVBG	R1, V1, 9	test instruction
00001F76	E310 8F20 0024		00001120	1688+	STG	R1, R1OUTPUT	save
00001F7C	B98D 0020			1689+	EPSW	R2, R0	extract psw
00001F80	5020 8ED8		000010D8	1690+	ST	R2, CCPSW	to save CC
00001F84	07FB			1691+	BR	R11	return
00001F88				1692+RE41	DC	OF	
00001F88				1693+	DROP	R5	
00001F88	00000002 DF8E1660			1694	DC	XL08' 00000002DF8E1660'	R1 result
00001F90	00000000 00000000			1695	DC	XL16' 0000000000000000000012340565600C'	V1 source
00001F98	00001234 0565600C			1696			
00001FA0				1697	VRR_I	VCVBG, 9, 0	LONG_MAX
00001FA0			00001FA0	1698+	DS	OFD	
00001FA0	0001FBC			1699+	USING	*, R5	base for test data and test routine
00001FA4	002A			1700+T42	DC	A(X42)	address of test routine
00001FA6	00			1701+	DC	H' 42'	test number
00001FA7	09			1702+	DC	XL1' 00'	
00001FA8	00			1703+	DC	HL1' 9'	&MB
00001FA9	07			1704+	DC	HL1' 0'	cc
00001FA9	07			1705+	DC	HL1' 7'	cc failed mask
00001FAA	E5C3E5C2 C7404040			1706+	DC	CL8' VCVBG'	instruction name
00001FB4	00000010			1707+	DC	A(16)	result length
00001FB8	00001FE0			1708+REA42	DC	A(REA42)	result address
00001FB8	00001FE0			1709+*			INSTRUCTION UNDER TEST ROUTINE
00001FBC				1710+X42	DS	OF	
00001FBC	E310 8EE8 0004		000010E8	1711+	LG	R1, R1FUDGE	pollute R1
00001FC2	E710 5048 0006		00001FE8	1712+	VL	V1, RE42+8	get V1 source
00001FC8	E611 0090 0052			1713+	VCVBG	R1, V1, 9	test instruction
00001FCE	E310 8F20 0024		00001120	1714+	STG	R1, R1OUTPUT	save
00001FD4	B98D 0020			1715+	EPSW	R2, R0	extract psw
00001FD8	5020 8ED8		000010D8	1716+	ST	R2, CCPSW	to save CC
00001FDC	07FB			1717+	BR	R11	return
00001FE0				1718+RE42	DC	OF	
00001FE0				1719+	DROP	R5	
00001FE0	7FFFFFFF FFFFFFFF			1720	DC	XL08' 7FFFFFFFFFFFFF'	R1 result
00001FE8	00000000 00009223			1721	DC	XL16' 000000000000000000009223372036854775807C'	V1 source
00001FF0	37203685 4775807C			1722			
00001FF8				1723	VRR_I	VCVBG, 9, 3	LONG_MIN
00001FF8			00001FF8	1724+	DS	OFD	
00001FF8	00002014			1725+	USING	*, R5	base for test data and test routine
00001FFC	002B			1726+T43	DC	A(X43)	address of test routine
00001FFE	00			1727+	DC	H' 43'	test number
00001FFF	09			1728+	DC	XL1' 00'	
00002000	03			1729+	DC	HL1' 9'	&MB
00002001	0E			1730+	DC	HL1' 3'	cc
00002001	0E			1731+	DC	HL1' 14'	cc failed mask
00002002	E5C3E5C2 C7404040			1732+	DC	CL8' VCVBG'	instruction name
0000200C	00000010			1733+	DC	A(16)	result length
00002010	00002038			1734+REA43	DC	A(REA43)	result address
00002014				1735+*			INSTRUCTION UNDER TEST ROUTINE
00002014	E310 8EE8 0004		000010E8	1736+X43	DS	OF	
00002014	E310 8EE8 0004			1737+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000201A	E710 5048 0006		00002040	1738+ VL V1, RE43+8			
00002020	E611 0090 0052			1739+ VCVBG R1, V1, 9	get V1 source		
00002026	E310 8F20 0024		00001120	1740+ STG R1, R1OUTPUT	test instruction		
0000202C	B98D 0020			1741+ EPSW R2, R0	save		
00002030	5020 8ED8		000010D8	1742+ ST R2, CCPFW	extract psw		
00002034	07FB			1743+ BR R11	to save CC		
00002038				1744+RE43 DC OF	return		
00002038				1745+ DROP R5			
00002038	80000000 00000000			1746 DC XL08' 8000000000000000'		R1 result	
00002040	00000000 00009223			1747 DC XL16' 0000000000009223372036854775808D'	V1 source		
00002048	37203685 4775808D			1748			
00002050		00002050		1749 VRR_I VCVBG, 11, 0		ULONG_MAX	
00002050				1750+ DS OFD			
00002050	0000206C			1751+ USING *, R5	base for test data and test routine		
00002054	002C			1752+T44 DC A(X44)	address of test routine		
00002056	00			1753+ DC H' 44'	test number		
00002057	0B			1754+ DC XL1' 00'			
00002058	00			1755+ DC HL1' 11'	&MB		
00002059	07			1756+ DC HL1' 0'	cc		
0000205A	E5C3E5C2 C7404040			1757+ DC HL1' 7'	cc failed mask		
00002064	00000010			1758+ DC CL8' VCVBG'	instruction name		
00002068	00002090			1759+ DC A(16)	result length		
0000206C				1760+REA44 DC A(RE44)	result address		
0000206C	E310 8EE8 0004	000010E8		1761+* 1762+X44 DS OF	INSTRUCTION UNDER TEST ROUTINE		
00002072	E710 5048 0006	00002098		1763+ LG R1, R1FUDGE	pollute R1		
00002078	E611 00B0 0052			1764+ VL V1, RE44+8	get V1 source		
0000207E	E310 8F20 0024		00001120	1765+ VCVBG R1, V1, 11	test instruction		
00002084	B98D 0020			1766+ STG R1, R1OUTPUT	save		
00002088	5020 8ED8		000010D8	1767+ EPSW R2, R0	extract psw		
0000208C	07FB			1768+ ST R2, CCPFW	to save CC		
00002090				1769+ BR R11	return		
00002090				1770+RE44 DC OF			
00002090				1771+ DROP R5			
00002090	FFFFFFFF FFFFFFFF			1772 DC XL08' FFFFFFFFFFFFFF'		R1 result	
00002098	00000000 00018446			1773 DC XL16' 0000000000018446744073709551615C'	V1 source		
000020A0	74407370 9551615C			1774			
000020A8		000020A8		1775 VRR_I VCVBG, 11, 3		ULONG_MAX +1	
000020A8				1776+ DS OFD			
000020A8	000020C4			1777+ USING *, R5	base for test data and test routine		
000020AC	002D			1778+T45 DC A(X45)	address of test routine		
000020AE	00			1779+ DC H' 45'	test number		
000020AF	0B			1780+ DC XL1' 00'			
000020B0	03			1781+ DC HL1' 11'	&MB		
000020B1	0E			1782+ DC HL1' 3'	cc		
000020B2	E5C3E5C2 C7404040			1783+ DC HL1' 14'	cc failed mask		
000020BC	00000010			1784+ DC CL8' VCVBG'	instruction name		
000020C0	000020E8			1785+ DC A(16)	result length		
000020C4				1786+REA45 DC A(RE45)	result address		
000020C4	E310 8EE8 0004	000010E8		1787+* 1788+X45 DS OF	INSTRUCTION UNDER TEST ROUTINE		
000020CA	E710 5048 0006	000020F0		1789+ LG R1, R1FUDGE	pollute R1		
000020D0	E611 00B0 0052			1790+ VL V1, RE45+8	get V1 source		
				1791+ VCVBG R1, V1, 11	test instruction		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000020D6	E310 8F20 0024		00001120	1792+ 1793+	STG EPSW	R1, R1OUTPUT R2, R0	save extract psw
000020DC	B98D 0020			000010D8	1794+ 1795+ 1796+RE45	ST BR DC	R2, CCPSW R11 OF
000020E0	5020 8ED8				1797+	DROP	R5
000020E4	07FB				1798	DC	XL08' 0000000000000000'
000020E8					1799	DC	XL16' 0000000000018446744073709551616C'
000020F0	00000000 00000000						R1 result
000020F8	00000000 00018446						V1 source
000020F8	74407370 9551616C						
					1800		
					1801	VRR_I	VCVBG, 11, 3
00002100					1802+	DS	OFD
00002100					1803+	USING	*, R5
00002100	0000211C	00002100			1804+T46	DC	A(X46)
00002104	002E				1805+	DC	H' 46'
00002106	00				1806+	DC	XL1' 00'
00002107	0B				1807+	DC	HL1' 11'
00002108	03				1808+	DC	HL1' 3'
00002109	0E				1809+	DC	HL1' 14'
0000210A	E5C3E5C2 C7404040				1810+	DC	CL8' VCVBG'
00002114	00000010				1811+	DC	A(16)
00002118	00002140				1812+RE46	DC	A(RE46)
					1813+*		
0000211C					1814+X46	DS	OF
0000211C	E310 8EE8 0004		000010E8	1815+	LG	R1, R1FUDGE	pollute R1
00002122	E710 5048 0006		00002148	1816+	VL	V1, RE46+8	get V1 source
00002128	E611 00B0 0052			1817+	VCVBG	R1, V1, 11	test instruction
0000212E	E310 8F20 0024		00001120	1818+	STG	R1, R1OUTPUT	save
00002134	B98D 0020			1819+	EPSW	R2, R0	extract psw
00002138	5020 8ED8		000010D8	1820+	ST	R2, CCPSW	to save CC
0000213C	07FB			1821+	BR	R11	return
00002140				1822+RE46	DC	OF	
00002140				1823+	DROP	R5	
00002140	00000000 0000000A			1824	DC	XL08' 000000000000000A'	R1 result
00002148	00000000 00018446			1825	DC	XL16' 0000000000018446744073709551626C'	V1 source
00002150	74407370 9551626C						
				1826			
00002158	00000000			1827	DC	F' 0'	END OF TABLE
0000215C	00000000			1828	DC	F' 0'	
				1829 *			
				1830 *	table of pointers to individual load test		
				1831 *			
00002160				1832 E6TESTS	DS	OF	
				1833	PTTABLE		
00002160				1834+TTABLE	DS	OF	
00002160	00001188			1835+	DC	A(T1)	address of test
00002164	000011E0			1836+	DC	A(T2)	address of test
00002168	00001238			1837+	DC	A(T3)	address of test
0000216C	00001290			1838+	DC	A(T4)	address of test
00002170	000012E8			1839+	DC	A(T5)	address of test
00002174	00001340			1840+	DC	A(T6)	address of test
00002178	00001398			1841+	DC	A(T7)	address of test
0000217C	000013F0			1842+	DC	A(T8)	address of test
00002180	00001448			1843+	DC	A(T9)	address of test
00002184	000014A0			1844+	DC	A(T10)	address of test
00002188	000014F8			1845+	DC	A(T11)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
0000218C	00001550		1846+	DC A(T12)	address of test
00002190	000015A8		1847+	DC A(T13)	address of test
00002194	00001600		1848+	DC A(T14)	address of test
00002198	00001658		1849+	DC A(T15)	address of test
0000219C	000016B0		1850+	DC A(T16)	address of test
000021A0	00001708		1851+	DC A(T17)	address of test
000021A4	00001760		1852+	DC A(T18)	address of test
000021A8	000017B8		1853+	DC A(T19)	address of test
000021AC	00001810		1854+	DC A(T20)	address of test
000021B0	00001868		1855+	DC A(T21)	address of test
000021B4	000018C0		1856+	DC A(T22)	address of test
000021B8	00001918		1857+	DC A(T23)	address of test
000021BC	00001970		1858+	DC A(T24)	address of test
000021C0	000019C8		1859+	DC A(T25)	address of test
000021C4	00001A20		1860+	DC A(T26)	address of test
000021C8	00001A78		1861+	DC A(T27)	address of test
000021CC	00001AD0		1862+	DC A(T28)	address of test
000021D0	00001B28		1863+	DC A(T29)	address of test
000021D4	00001B80		1864+	DC A(T30)	address of test
000021D8	00001BD8		1865+	DC A(T31)	address of test
000021DC	00001C30		1866+	DC A(T32)	address of test
000021E0	00001C88		1867+	DC A(T33)	address of test
000021E4	00001CE0		1868+	DC A(T34)	address of test
000021E8	00001D38		1869+	DC A(T35)	address of test
000021EC	00001D90		1870+	DC A(T36)	address of test
000021F0	00001DE8		1871+	DC A(T37)	address of test
000021F4	00001E40		1872+	DC A(T38)	address of test
000021F8	00001E98		1873+	DC A(T39)	address of test
000021FC	00001EF0		1874+	DC A(T40)	address of test
00002200	00001F48		1875+	DC A(T41)	address of test
00002204	00001FA0		1876+	DC A(T42)	address of test
00002208	00001FF8		1877+	DC A(T43)	address of test
0000220C	00002050		1878+	DC A(T44)	address of test
00002210	000020A8		1879+	DC A(T45)	address of test
00002214	00002100		1880+	DC A(T46)	address of test
			1881+*		
00002218	00000000		1882+	DC A(0)	END OF TABLE
0000221C	00000000		1883+	DC A(0)	
			1884		
00002220	00000000		1885	DC F' 0'	END OF TABLE
00002224	00000000		1886	DC F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				1888 ****	*****	*****
				1889 *	Register equates	
				1890 ****	*****	*****
	00000000	00000001	1892	R0	EQU	0
	00000001	00000001	1893	R1	EQU	1
	00000002	00000001	1894	R2	EQU	2
	00000003	00000001	1895	R3	EQU	3
	00000004	00000001	1896	R4	EQU	4
	00000005	00000001	1897	R5	EQU	5
	00000006	00000001	1898	R6	EQU	6
	00000007	00000001	1899	R7	EQU	7
	00000008	00000001	1900	R8	EQU	8
	00000009	00000001	1901	R9	EQU	9
	0000000A	00000001	1902	R10	EQU	10
	0000000B	00000001	1903	R11	EQU	11
	0000000C	00000001	1904	R12	EQU	12
	0000000D	00000001	1905	R13	EQU	13
	0000000E	00000001	1906	R14	EQU	14
	0000000F	00000001	1907	R15	EQU	15
				1909 ****	*****	*****
				1910 *	Register equates	
				1911 ****	*****	*****
	00000000	00000001	1913	V0	EQU	0
	00000001	00000001	1914	V1	EQU	1
	00000002	00000001	1915	V2	EQU	2
	00000003	00000001	1916	V3	EQU	3
	00000004	00000001	1917	V4	EQU	4
	00000005	00000001	1918	V5	EQU	5
	00000006	00000001	1919	V6	EQU	6
	00000007	00000001	1920	V7	EQU	7
	00000008	00000001	1921	V8	EQU	8
	00000009	00000001	1922	V9	EQU	9
	0000000A	00000001	1923	V10	EQU	10
	0000000B	00000001	1924	V11	EQU	11
	0000000C	00000001	1925	V12	EQU	12
	0000000D	00000001	1926	V13	EQU	13
	0000000E	00000001	1927	V14	EQU	14
	0000000F	00000001	1928	V15	EQU	15
	00000010	00000001	1929	V16	EQU	16
	00000011	00000001	1930	V17	EQU	17
	00000012	00000001	1931	V18	EQU	18
	00000013	00000001	1932	V19	EQU	19
	00000014	00000001	1933	V20	EQU	20
	00000015	00000001	1934	V21	EQU	21

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
		00000016	00000001	1935 V22	EQU	22
		00000017	00000001	1936 V23	EQU	23
		00000018	00000001	1937 V24	EQU	24
		00000019	00000001	1938 V25	EQU	25
		0000001A	00000001	1939 V26	EQU	26
		0000001B	00000001	1940 V27	EQU	27
		0000001C	00000001	1941 V28	EQU	28
		0000001D	00000001	1942 V29	EQU	29
		0000001E	00000001	1943 V30	EQU	30
		0000001F	00000001	1944 V31	EQU	31
				1945		
				1946	END	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES																	
BEGIN	I	00000200	2	151	116	147	148	149														
CC	U	00000008	1	512	262																	
CCFOUND	X	000010E0	1	484	249	269																
CCMASK	U	00000009	1	513	220																	
CCMSG	U	00000322	1	238	232																	
CCPRTEXP	C	0000108A	1	464	266																	
CCPRTGOT	C	0000109A	1	467	273																	
CCPRTLINE	C	00001047	16	459	469	276																
CCPRTLNG	U	00000055	1	469	275																	
CCPRTNAME	C	00001074	8	462	259																	
CCPRTNUM	C	00001057	3	460	257																	
CCPSW	F	000010D8	4	483	246	644	670	696	722	748	774	800	826	852	879	905	931					
					957	983	1009	1035	1061	1087	1117	1143	1169	1195	1221	1247	1273					
					1299	1325	1351	1377	1403	1429	1455	1482	1508	1534	1560	1586	1612					
					1638	1664	1690	1716	1742	1768	1794	1820										
CTRL0	F	00000534	4	405	161	162	163	164														
DECNUM	C	000010C8	16	479	254	256	263	265	270	272	288	290	297	299								
E6TEST	4	00000000	28	507	212																	
E6TESTS	F	00002160	4	1832	203																	
EDIT	X	0000109C	18	474	255	264	271	289	298													
ENDTEST	U	0000040C	1	319	208																	
EOJ	I	00000518	4	395	196	322																
EOJPSW	D	00000508	8	393	395																	
FAILCONT	U	000003FC	1	309	279																	
FAILED	F	00001000	4	435	311	320																
FAILMSG	U	000003B2	1	286	227																	
FAILPSW	D	00000520	8	397	399																	
FAILTEST	I	00000530	4	399	323																	
FB0001	F	00000288	8	180	184	185	187															
IMAGE	I	00000000	8744	0																		
K	U	00000400	1	418	419	420	421															
K64	U	00010000	1	420																		
MB	U	00000007	1	511	240	296																
MB	U	00100000	1	421																		
MSG	I	00000450	4	355	195	338																
MSGCMD	C	0000049E	9	385	368	369																
MSGMSG	C	000004A7	95	386	362	383	360															
MSGM/C	I	00000498	6	383	366																	
MSGOK	I	00000466	2	364	361																	
MSGRET	I	00000486	4	379	372	375																
MSGSAVE	F	0000048C	4	382	358	379																
NEXTE6	U	000002DC	1	205	230	314																
OPNAME	C	0000000A	8	515	259	293																
PAGE	U	00001000	1	419																		
PRT3	C	000010B2	18	477	255	256	257	264	265	266	271	272	273	289	290	291	298					
					299	300																
PRTLINE	C	00001008	16	444	451	303																
PRTLNG	U	0000003F	1	451	302																	
PRTMB	C	00001044	2	449	300																	
PRTNAME	C	00001033	8	447	293																	
PRTNUM	C	00001018	3	445	291																	
RO	U	00000000	1	1892	110	161	164	184	186	187	188	193	210	214	215	275	302					
					310	311	337	339	355	358	360	362	364	379	643	669	695					
					721	747	773	799	825	851	878	904	930	956	982	1008	1034					
					1060	1086	1116	1142	1168	1194	1220	1246	1272	1298	1324	1350	1376					
					1402	1428	1454	1481	1507	1533	1559	1585	1611	1637	1663	1689	1715					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	1741	1767	1793	1819	194	220	221	222	225	226	239	240	241	246	247	248	249	
R1	U	00000001	1	1893		276	303	320	321	369	383	639	641	642	644	665	667	668	691				
						693	694	717	719	720	743	745	746	769	771	772	795	797					
						798	821	823	824	847	849	850	874	876	877	900	902	903					
						926	928	929	952	954	955	978	980	981	1004	1006	1007	1030					
						1032	1033	1056	1058	1059	1082	1084	1085	1112	1114	1115	1138	1140					
						1141	1164	1166	1167	1190	1192	1193	1216	1218	1219	1242	1244	1245					
						1268	1270	1271	1294	1296	1297	1320	1322	1323	1346	1348	1349	1372					
						1374	1375	1398	1400	1401	1424	1426	1427	1450	1452	1453	1477	1479					
						1480	1503	1505	1506	1529	1531	1532	1555	1557	1558	1581	1583	1584					
						1607	1609	1610	1633	1635	1636	1659	1661	1662	1685	1687	1688	1711					
						1713	1714	1737	1739	1740	1763	1765	1766	1789	1791	1792	1815	1817					
						1818																	
R10	U	0000000A	1	1902		149	158	159															
R11	U	0000000B	1	1903		217	218	645	671	697	723	749	775	801	827	853	880	906					
						932	958	984	1010	1036	1062	1088	1118	1144	1170	1196	1222	1248					
						1274	1300	1326	1352	1378	1404	1430	1456	1483	1509	1535	1561	1587					
R12	U	0000000C	1	1904		1613	1639	1665	1691	1717	1743	1769	1795	1821									
R13	U	0000000D	1	1905																			
R14	U	0000000E	1	1906																			
R15	U	0000000F	1	1907		277	304	332	342	343													
R1FUDGE	X	000010E8	8	490		639	665	691	717	743	769	795	821	847	874	900	926	952					
						978	1004	1030	1056	1082	1112	1138	1164	1190	1216	1242	1268	1294					
						1320	1346	1372	1398	1424	1450	1477	1503	1529	1555	1581	1607	1633					
R10OUTPUT	F	00001120	8	494		1659	1685	1711	1737	1763	1789	1815											
						226	642	668	694	720	746	772	798	824	850	877	903	929					
						955	981	1007	1033	1059	1085	1115	1141	1167	1193	1219	1245	1271					
						1297	1323	1349	1375	1401	1427	1453	1480	1506	1532	1558	1584	1610					
R2	U	00000002	1	1894		1636	1662	1688	1714	1740	1766	1792	1818										
						195	253	254	261	262	263	268	269	270	287	288	295	296					
						297	337	338	339	356	358	364	365	366	368	374	379	380					
						643	644	669	670	695	696	721	722	747	748	773	774	799					
						800	825	826	851	852	878	879	904	905	930	931	956	957					
						982	983	1008	1009	1034	1035	1060	1061	1086	1087	1116	1117	1142					
						1143	1168	1169	1194	1195	1220	1221	1246	1247	1272	1273	1298	1299					
						1324	1325	1350	1351	1376	1377	1402	1403	1428	1429	1454	1455	1481					
						1482	1507	1508	1533	1534	1559	1560	1585	1586	1611	1612	1637	1638					
						1663	1664	1689	1690	1715	1716	1741	1742	1767	1768	1793	1794	1819					
						1820																	
R3	U	00000003	1	1895																			
R4	U	00000004	1	1896																			
R5	U	00000005	1	1897		206	207	212	333	341	627	647	653	673	679	699	705	725					
						731	751	757	777	783	803	809	829	835	855	862	882	888					
						908	914	934	940	960	966	986	992	1012	1018	1038	1044	1064					
						1070	1090	1100	1120	1126	1146	1152	1172	1178	1198	1204	1224	1230					
						1250	1256	1276	1282	1302	1308	1328	1334	1354	1360	1380	1386	1406					
						1412	1432	1438	1458	1465	1485	1491	1511	1517	1537	1543	1563	1569					
						1589	1595	1615	1621	1641	1647	1667	1673	1693	1699	1719	1725	1745					
						1751	1771	1777	1797	1803	1823												
R6	U	00000006	1	1898																			
R7	U	00000007	1	1899</																			

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE10	F	000014E0	4	881	871 875
RE11	F	00001538	4	907	897 901
RE12	F	00001590	4	933	923 927
RE13	F	000015E8	4	959	949 953
RE14	F	00001640	4	985	975 979
RE15	F	00001698	4	1011	1001 1005
RE16	F	000016F0	4	1037	1027 1031
RE17	F	00001748	4	1063	1053 1057
RE18	F	000017A0	4	1089	1079 1083
RE19	F	000017F8	4	1119	1109 1113
RE2	F	00001220	4	672	662 666
RE20	F	00001850	4	1145	1135 1139
RE21	F	000018A8	4	1171	1161 1165
RE22	F	00001900	4	1197	1187 1191
RE23	F	00001958	4	1223	1213 1217
RE24	F	000019B0	4	1249	1239 1243
RE25	F	00001A08	4	1275	1265 1269
RE26	F	00001A60	4	1301	1291 1295
RE27	F	00001AB8	4	1327	1317 1321
RE28	F	00001B10	4	1353	1343 1347
RE29	F	00001B68	4	1379	1369 1373
RE3	F	00001278	4	698	688 692
RE30	F	00001BC0	4	1405	1395 1399
RE31	F	00001C18	4	1431	1421 1425
RE32	F	00001C70	4	1457	1447 1451
RE33	F	00001CC8	4	1484	1474 1478
RE34	F	00001D20	4	1510	1500 1504
RE35	F	00001D78	4	1536	1526 1530
RE36	F	00001DD0	4	1562	1552 1556
RE37	F	00001E28	4	1588	1578 1582
RE38	F	00001E80	4	1614	1604 1608
RE39	F	00001ED8	4	1640	1630 1634
RE4	F	000012D0	4	724	714 718
RE40	F	00001F30	4	1666	1656 1660
RE41	F	00001F88	4	1692	1682 1686
RE42	F	00001FE0	4	1718	1708 1712
RE43	F	00002038	4	1744	1734 1738
RE44	F	00002090	4	1770	1760 1764
RE45	F	000020E8	4	1796	1786 1790
RE46	F	00002140	4	1822	1812 1816
RE5	F	00001328	4	750	740 744
RE6	F	00001380	4	776	766 770
RE7	F	000013D8	4	802	792 796
RE8	F	00001430	4	828	818 822
RE9	F	00001488	4	854	844 848
REA1	A	000011A0	4	636	
REA10	A	000014B8	4	871	
REA11	A	00001510	4	897	
REA12	A	00001568	4	923	
REA13	A	000015C0	4	949	
REA14	A	00001618	4	975	
REA15	A	00001670	4	1001	
REA16	A	000016C8	4	1027	
REA17	A	00001720	4	1053	
REA18	A	00001778	4	1079	
REA19	A	000017D0	4	1109	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA2	A	000011F8	4	662	
REA20	A	00001828	4	1135	
REA21	A	00001880	4	1161	
REA22	A	000018D8	4	1187	
REA23	A	00001930	4	1213	
REA24	A	00001988	4	1239	
REA25	A	000019E0	4	1265	
REA26	A	00001A38	4	1291	
REA27	A	00001A90	4	1317	
REA28	A	00001AE8	4	1343	
REA29	A	00001B40	4	1369	
REA3	A	00001250	4	688	
REA30	A	00001B98	4	1395	
REA31	A	00001BF0	4	1421	
REA32	A	00001C48	4	1447	
REA33	A	00001CA0	4	1474	
REA34	A	00001CF8	4	1500	
REA35	A	00001D50	4	1526	
REA36	A	00001DA8	4	1552	
REA37	A	00001E00	4	1578	
REA38	A	00001E58	4	1604	
REA39	A	00001EB0	4	1630	
REA4	A	000012A8	4	714	
REA40	A	00001F08	4	1656	
REA41	A	00001F60	4	1682	
REA42	A	00001FB8	4	1708	
REA43	A	00002010	4	1734	
REA44	A	00002068	4	1760	
REA45	A	000020C0	4	1786	
REA46	A	00002118	4	1812	
REA5	A	00001300	4	740	
REA6	A	00001358	4	766	
REA7	A	000013B0	4	792	
REA8	A	00001408	4	818	
REA9	A	00001460	4	844	
READDR	A	00000018	4	518	225
REG2LOW	U	000000DD	1	425	
REG2PATT	U	AABBCCDD	1	424	
RELEN	A	00000014	4	517	
RPTDWSAV	D	00000440	8	348	337 339
RPTERROR	I	0000041A	4	332	277 304
RPTSAVE	F	00000438	4	345	332 342
RPTSVR5	F	0000043C	4	346	333 341
SKL0001	U	00000054	1	177	193
SKT0001	C	0000022A	26	174	177 194
SVOLDPSW	U	00000140	0	112	
T1	A	00001188	4	628	1835
T10	A	000014A0	4	863	1844
T11	A	000014F8	4	889	1845
T12	A	00001550	4	915	1846
T13	A	000015A8	4	941	1847
T14	A	00001600	4	967	1848
T15	A	00001658	4	993	1849
T16	A	000016B0	4	1019	1850
T17	A	00001708	4	1045	1851
T18	A	00001760	4	1071	1852

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
T19	A	000017B8	4	1101	1853
T2	A	000011E0	4	654	1836
T20	A	00001810	4	1127	1854
T21	A	00001868	4	1153	1855
T22	A	000018C0	4	1179	1856
T23	A	00001918	4	1205	1857
T24	A	00001970	4	1231	1858
T25	A	000019C8	4	1257	1859
T26	A	00001A20	4	1283	1860
T27	A	00001A78	4	1309	1861
T28	A	00001AD0	4	1335	1862
T29	A	00001B28	4	1361	1863
T3	A	00001238	4	680	1837
T30	A	00001B80	4	1387	1864
T31	A	00001BD8	4	1413	1865
T32	A	00001C30	4	1439	1866
T33	A	00001C88	4	1466	1867
T34	A	00001CE0	4	1492	1868
T35	A	00001D38	4	1518	1869
T36	A	00001D90	4	1544	1870
T37	A	00001DE8	4	1570	1871
T38	A	00001E40	4	1596	1872
T39	A	00001E98	4	1622	1873
T4	A	00001290	4	706	1838
T40	A	00001EF0	4	1648	1874
T41	A	00001F48	4	1674	1875
T42	A	00001FA0	4	1700	1876
T43	A	00001FF8	4	1726	1877
T44	A	00002050	4	1752	1878
T45	A	000020A8	4	1778	1879
T46	A	00002100	4	1804	1880
T5	A	000012E8	4	732	1839
T6	A	00001340	4	758	1840
T7	A	00001398	4	784	1841
T8	A	000013F0	4	810	1842
T9	A	00001448	4	836	1843
TESTCC	I	0000031E	4	232	222
TESTING	F	00001004	4	436	215
TESTREST	U	00000306	1	224	242
TNUM	H	00000004	2	509	214
TSUB	A	00000000	4	508	217
TTABLE	F	00002160	4	1834	
V0	U	00000000	1	1913	
V1	U	00000001	1	1914	640 641 666 667 692 693 718 719 744 745 770 771 796 797 822 823 848 849 875 876 901 902 927 928 953 954 979 980 1005 1006 1031 1032 1057 1058 1083 1084 1113 1114 1139 1140 1165 1166 1191 1192 1217 1218 1243 1244 1269 1270 1295 1296 1321 1322 1347 1348 1373 1374 1399 1400 1425 1426 1451 1452 1478 1479 1504 1505 1530 1531 1556 1557 1582 1583 1608 1609 1634 1635 1660 1661 1686 1687 1712 1713 1738 1739 1764 1765 1790 1791 1816 1817
V10	U	0000000A	1	1923	
V11	U	0000000B	1	1924	
V12	U	0000000C	1	1925	
V13	U	0000000D	1	1926	
V14	U	0000000E	1	1927	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V15	U	0000000F	1	1928	
V16	U	00000010	1	1929	
V17	U	00000011	1	1930	
V18	U	00000012	1	1931	
V19	U	00000013	1	1932	
V1FUDGE	X	00001138	16	496	
V1FUDGEB	X	00001148	16	497	
V1INPUT	C	00001158	16	498	
V10UTPUT	X	00001100	16	492	
V2	U	00000002	1	1915	
V20	U	00000014	1	1933	
V21	U	00000015	1	1934	
V22	U	00000016	1	1935	
V23	U	00000017	1	1936	
V24	U	00000018	1	1937	
V25	U	00000019	1	1938	
V26	U	0000001A	1	1939	
V27	U	0000001B	1	1940	
V28	U	0000001C	1	1941	
V29	U	0000001D	1	1942	
V3	U	00000003	1	1916	
V30	U	0000001E	1	1943	
V31	U	0000001F	1	1944	
V4	U	00000004	1	1917	
V5	U	00000005	1	1918	
V6	U	00000006	1	1919	
V7	U	00000007	1	1920	
V8	U	00000008	1	1921	
V9	U	00000009	1	1922	
X0001	U	000002B0	1	183	171 184
X1	F	000011A4	4	638	628
X10	F	000014BC	4	873	863
X11	F	00001514	4	899	889
X12	F	0000156C	4	925	915
X13	F	000015C4	4	951	941
X14	F	0000161C	4	977	967
X15	F	00001674	4	1003	993
X16	F	000016CC	4	1029	1019
X17	F	00001724	4	1055	1045
X18	F	0000177C	4	1081	1071
X19	F	000017D4	4	1111	1101
X2	F	000011FC	4	664	654
X20	F	0000182C	4	1137	1127
X21	F	00001884	4	1163	1153
X22	F	000018DC	4	1189	1179
X23	F	00001934	4	1215	1205
X24	F	0000198C	4	1241	1231
X25	F	000019E4	4	1267	1257
X26	F	00001A3C	4	1293	1283
X27	F	00001A94	4	1319	1309
X28	F	00001AEC	4	1345	1335
X29	F	00001B44	4	1371	1361
X3	F	00001254	4	690	680
X30	F	00001B9C	4	1397	1387
X31	F	00001BF4	4	1423	1413
X32	F	00001C4C	4	1449	1439

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X33	F	00001CA4	4	1476	1466
X34	F	00001CFC	4	1502	1492
X35	F	00001D54	4	1528	1518
X36	F	00001DAC	4	1554	1544
X37	F	00001E04	4	1580	1570
X38	F	00001E5C	4	1606	1596
X39	F	00001EB4	4	1632	1622
X4	F	000012AC	4	716	706
X40	F	00001F0C	4	1658	1648
X41	F	00001F64	4	1684	1674
X42	F	00001FBC	4	1710	1700
X43	F	00002014	4	1736	1726
X44	F	0000206C	4	1762	1752
X45	F	000020C4	4	1788	1778
X46	F	0000211C	4	1814	1804
X5	F	00001304	4	742	732
X6	F	0000135C	4	768	758
X7	F	000013B4	4	794	784
X8	F	0000140C	4	820	810
X9	F	00001464	4	846	836
XC0001	U	000002D8	1	197	189
ZVE6TST	J	00000000	8744	109	112 114 118 122 434 110
=A(E6TESTS)	A	00000540	4	410	203
=AL2(L' MSGMSG)	R	0000054E	2	414	360
=F' 1'	F	00000544	4	411	241 310
=F' 2'	F	0000053C	4	409	188
=H' 0'	H	0000054C	2	413	355
=XL4' 3'	X	00000548	4	412	248

MACRO DEFN REFERENCES

FCHECK	61	170
PTTABLE	587	1833
VRR_I	532	625 651 677 703 729 755 781 807 833 860 886 912 938 964 990 1016 1042 1068 1098 1124 1150 1176 1202 1228 1254 1280 1306 1332 1358 1384 1410 1436 1463 1489 1515 1541 1567 1593 1619 1645 1671 1697 1723 1749 1775 1801

DESC	SYMBOL	SIZE	POS	ADDR
------	--------	------	-----	------

Entry: 0

Image	IMAGE	8744	0000-2227	0000-2227
Region		8744	0000-2227	0000-2227
CSECT	ZVE6TST	8744	0000-2227	0000-2227

STMT	FILE NAME
1	/home/tn529/sharedvfp/tests/zvector-e6-11-convertbinary.asm

** NO ERRORS FOUND **